

Elipsometrija tankih slojeva organskih poluvodiča

Marta Nikić

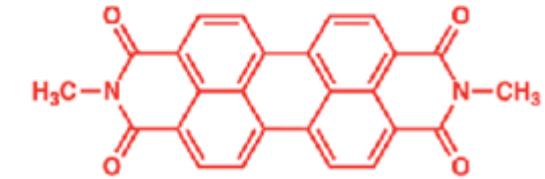
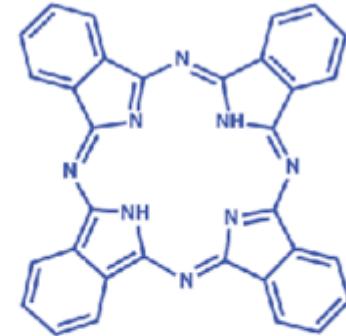
Mentor: dr. sc. Jordi Sancho Parramon

Laboratorij za optiku i optički tanke slojeve

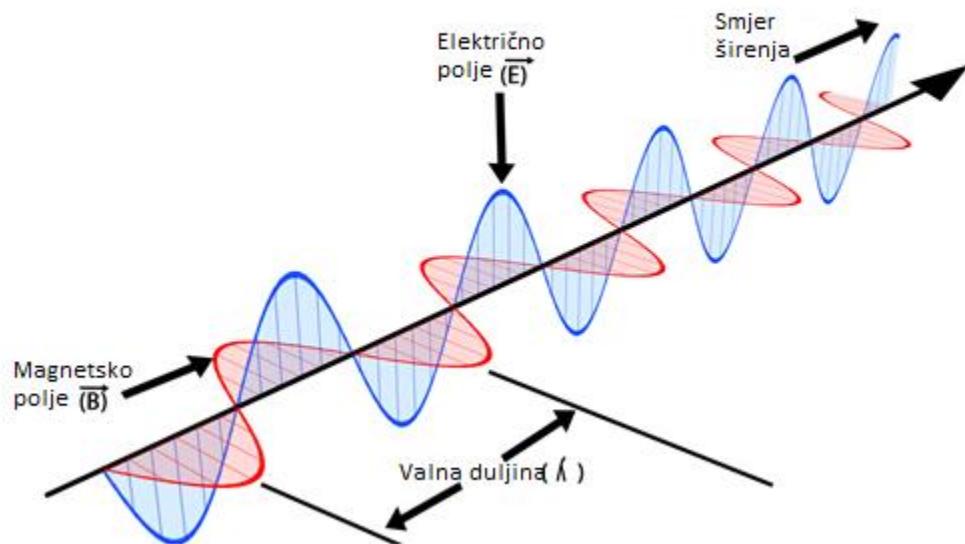
Institut Ruđer Bošković

Ciljevi

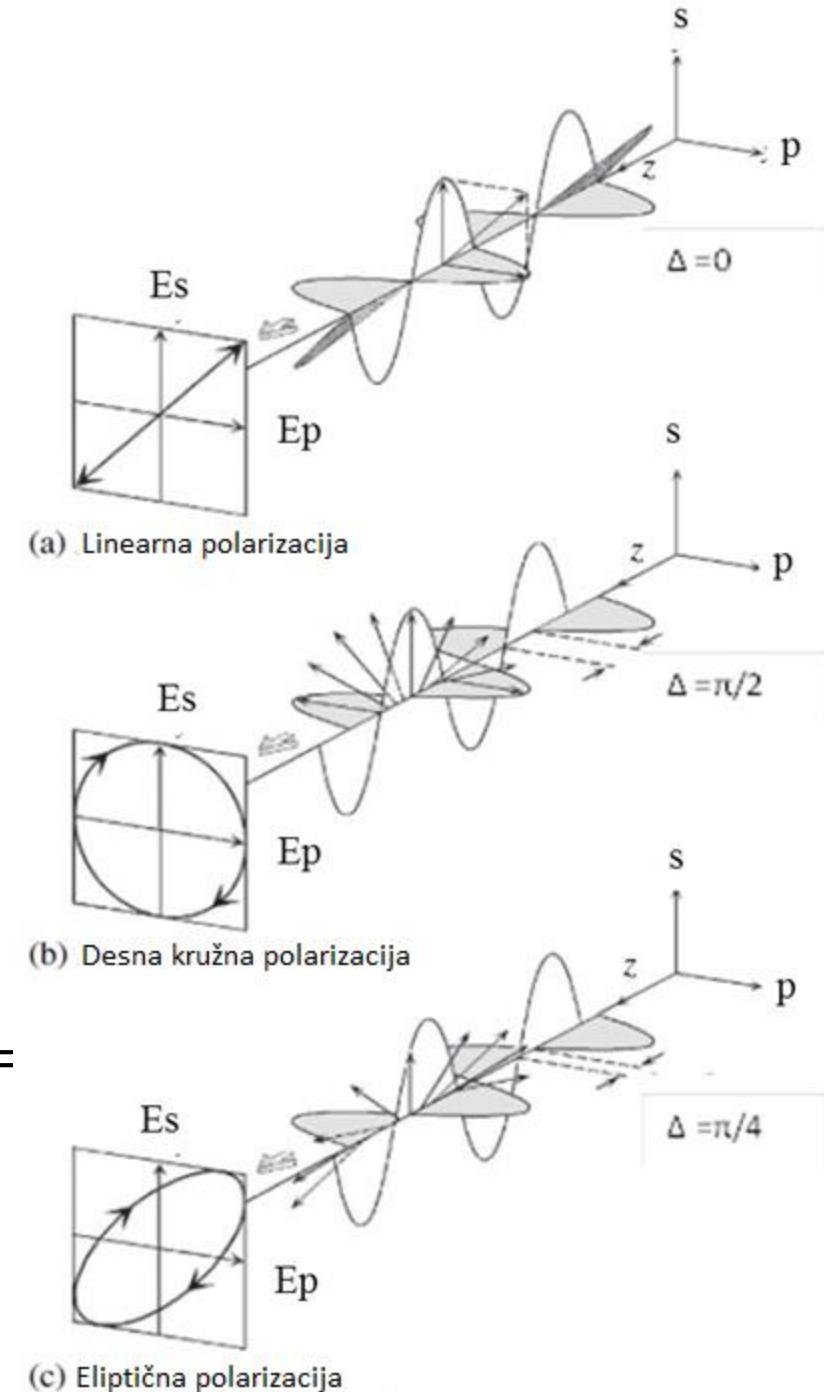
- Određivanje opičkih svojstva H₂Pc-a i PTCDI-a
 - Dielektrična funkcija
 - Utjecaj temperature; 20°C ili -160°C?
 - Debljina?
 - Hrapavost?
 - Rad uređaja?



EM ravni val i polarizacija svjetlosti

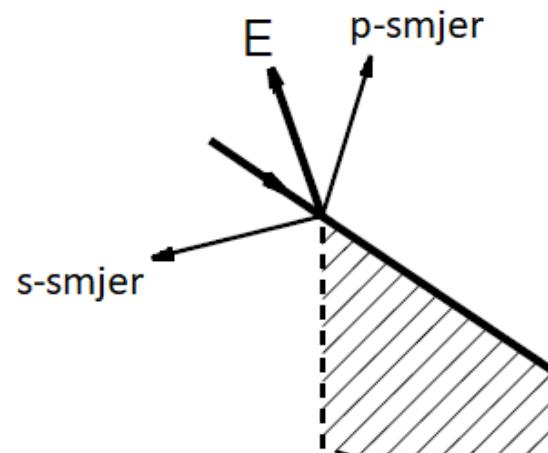


$$\vec{E}(\vec{r}, t) = \vec{E}_0 \exp\left(\frac{i2\pi\tilde{n}}{\lambda} \vec{q} \cdot \vec{r}\right) \exp(-i\omega t)$$

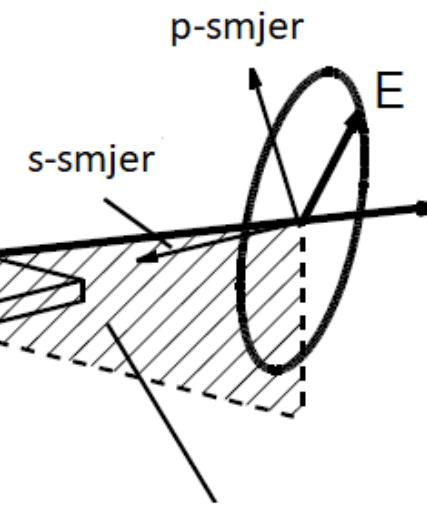


Što je elipsometrija?

1. Linearno polarizirana svjetlost...



3. Eliptično polarizirana svjetlost!



2. Refleksija od površine...

$$\vec{E} = \begin{bmatrix} \tilde{E}_p \\ \tilde{E}_s \end{bmatrix}$$

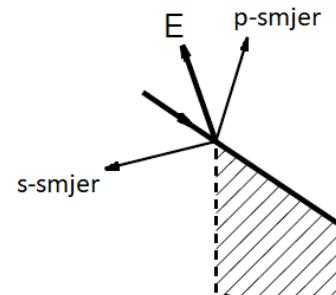
Što elipsometar mjeri?

- Promjena polarizacijskog stanja svjetlosti reflektirane s površine uzorka
- Mjerenje vrijednosti se izražavaju preko psi ψ i delta Δ varijabli

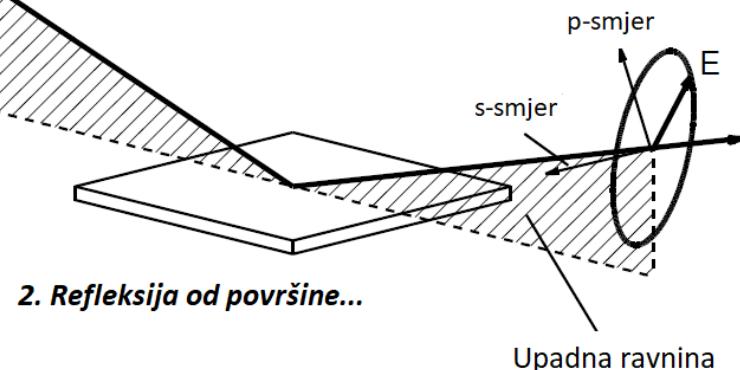
$$\tilde{\rho} = \frac{\tilde{R}_p}{\tilde{R}_s} = \tan \psi e^{i\Delta}$$

$$\vec{E} = \begin{bmatrix} \tilde{E}_p \\ \tilde{E}_s \end{bmatrix}$$

1. Linearno polarizirana svjetlost...



3. Eliptično polarizirana svjetlost!

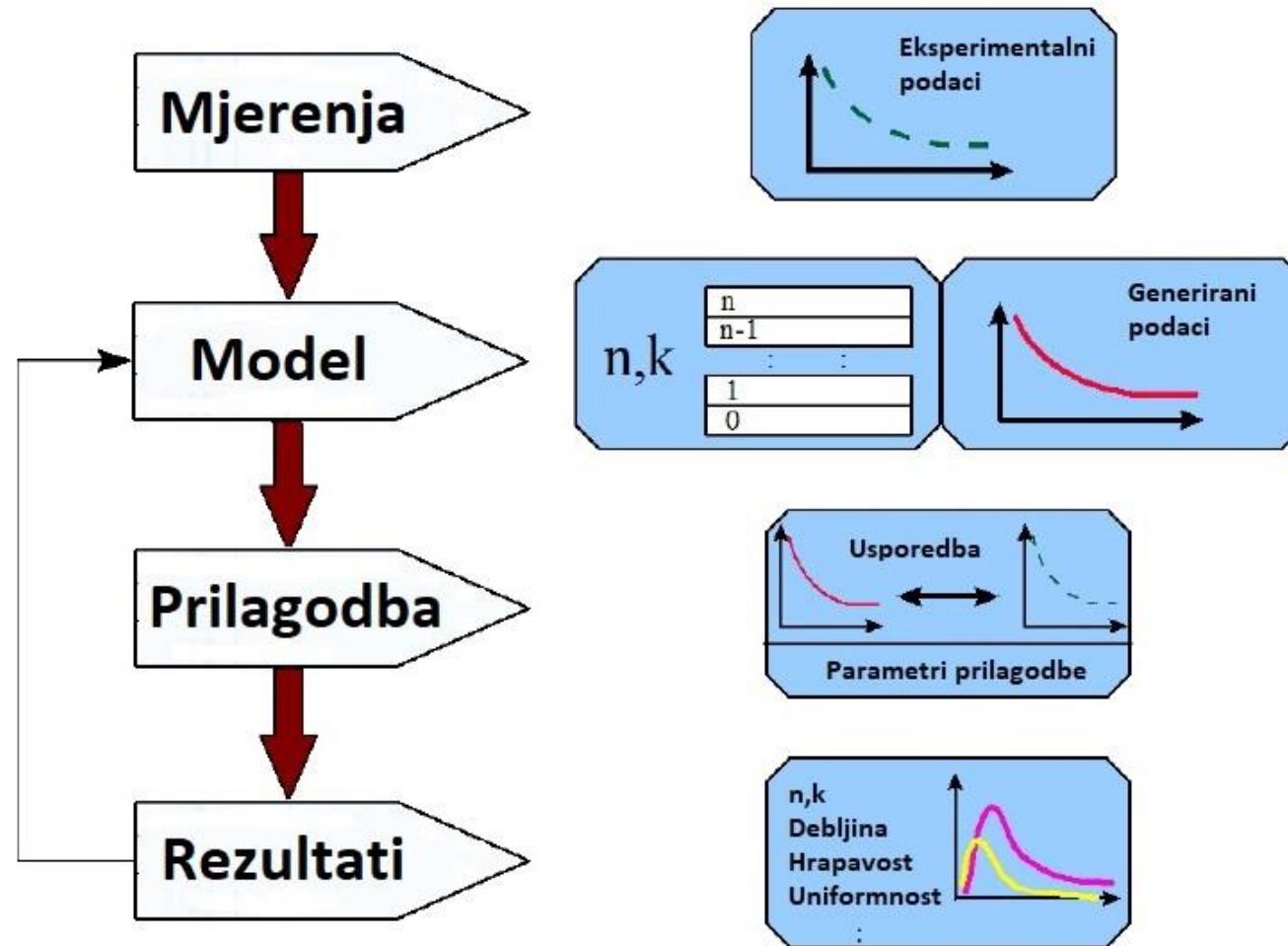


2. Refleksija od površine...

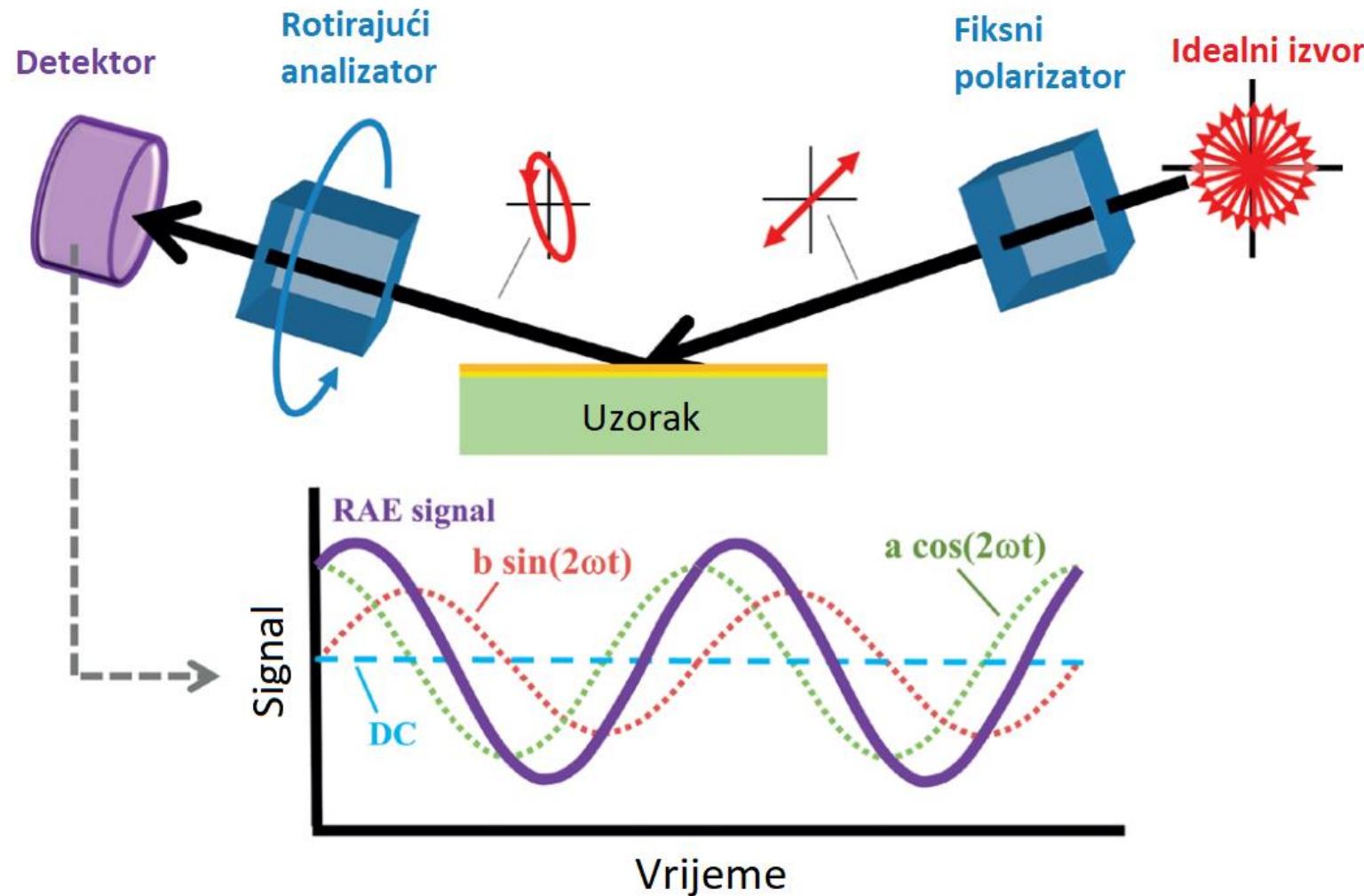
Koji se parametri mogu odrediti?

- Optičke konstante (n , k or ϵ_1 , ϵ_2)
- Debljina tankog sloja
- Koncentracija dopiranja
- Površinska ili između slojeva hrapavost
- Optička anizotropija

Generalna procedura za optičke eksperimente



Elipsometar s rotirajućim analizatorom



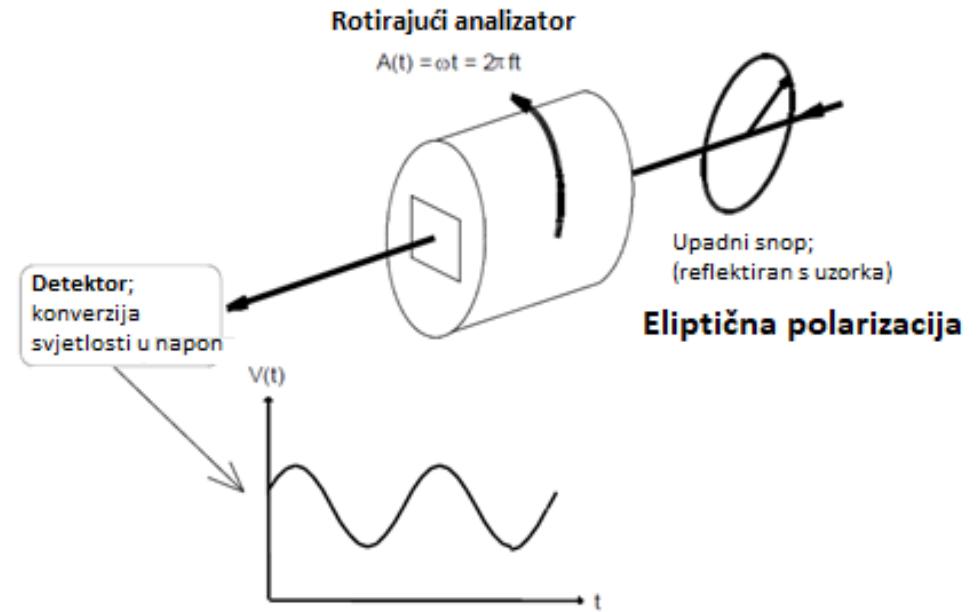
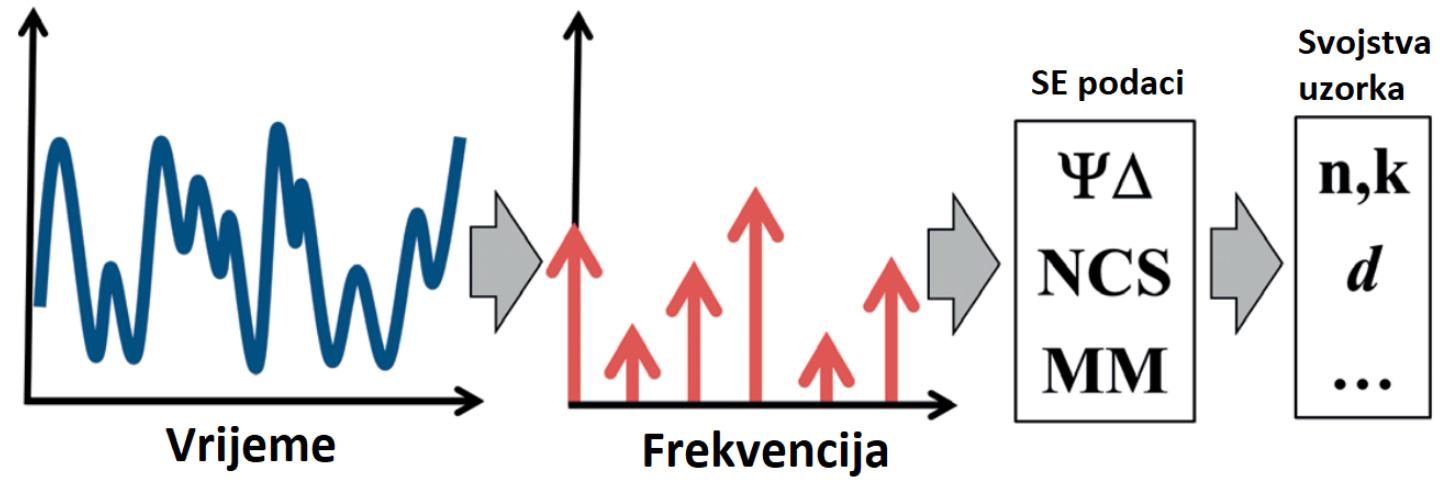
$$\tilde{\rho} = \frac{\tilde{R}_p}{\tilde{R}_s} = \tan \psi e^{i\Delta}$$

Mjerenja polarizacije

$$V(t) = DC + a \cdot \cos(2\omega t) + b \cdot \sin(2\omega t)$$

$$\alpha = \frac{a}{DC} = \frac{\tan^2(\psi) - \tan^2(P)}{\tan^2(\psi) + \tan^2(P)}$$

$$\beta = \frac{b}{DC} = \frac{2\tan(\psi) \cos(\Delta) \tan(P)}{\tan^2(\psi) + \tan^2(P)}$$



Još malo matematike...

$$\alpha = \frac{a}{DC} = \frac{\tan^2(\psi) - \tan^2(P)}{\tan^2(\psi) + \tan^2(P)}$$

$$\beta = \frac{b}{DC} = \frac{2\tan(\psi) \cos(\Delta) \tan(P)}{\tan^2(\psi) + \tan^2(P)}$$



$$\tan\psi = \sqrt{\frac{1+\alpha}{1-\alpha}} |\tan P|$$

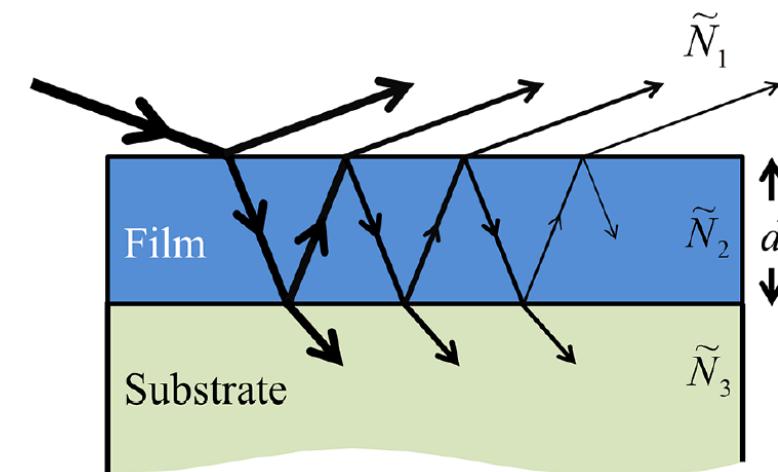
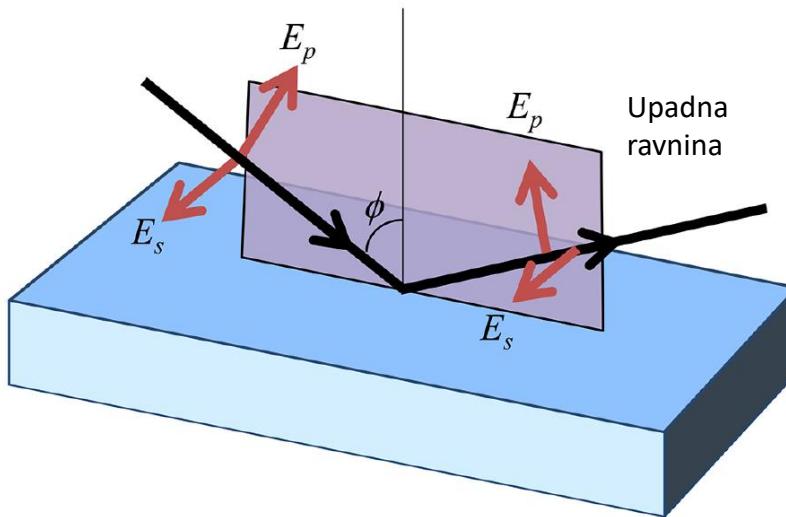
$$\cos\Delta = \frac{\beta}{\sqrt{1-\alpha^2}} \cdot \frac{\tan P}{|\tan P|}$$

$$\tilde{\rho} = \frac{\tilde{R}_p}{\tilde{R}_s} = \tan \psi e^{i\Delta}$$



Fresnelovi koeficijenti → optička svojstva?

$$\tan \psi e^{i\Delta} = \frac{\tilde{R}_p}{\tilde{R}_s} \rightarrow n, k \text{ ili } \varepsilon_1, \varepsilon_2 ?$$



$$r_{p,12} = \frac{E_p^{refl}}{E_p^{inc}} = \frac{\tilde{n}_2 \cos \Phi_1 - \tilde{n}_1 \cos \Phi_2}{\tilde{n}_2 \cos \Phi_1 + \tilde{n}_1 \cos \Phi_2}$$

$$r_{s,12} = \frac{E_s^{refl}}{E_s^{inc}} = \frac{\tilde{n}_1 \cos \Phi_1 - \tilde{n}_2 \cos \Phi_2}{\tilde{n}_1 \cos \Phi_1 + \tilde{n}_2 \cos \Phi_2}$$

$$R_s = \frac{r_{s,12} + r_{s,23} e^{-i2\beta}}{1 + r_{s,12} r_{s,23} e^{-i2\beta}}$$

$$R_p = \frac{r_{p,12} + r_{p,23} e^{-i2\beta}}{1 + r_{p,12} r_{p,23} e^{-i2\beta}}$$

$$\beta = 2\pi \frac{d}{\lambda} \tilde{n}_2 \cos \Phi_2$$

Regresijska analiza optičkih podataka

- Levenberg-Marquardt algoritam
- Maksimalan procijenitelj vjerovatnosti → srednja kvadratna pogreška, MSE

$$MSE = \sqrt{\frac{1}{2N - M} \sum_{i=1}^N \left[\left(\frac{\psi_i^{mod} - \psi_i^{exp}}{\sigma_{\psi,i}^{exp}} \right)^2 + \left(\frac{\Delta_i^{mod} - \Delta_i^{exp}}{\sigma_{\Delta,i}^{exp}} \right)^2 \right]}$$

N = number of (ψ, Δ) pairs

M = number of parameters in the model

σ = standard deviations on the experimental data points

Što su optičke konstante?

- Parametri koji karakteriziraju ponašanje materijala u prisutnosti vanjskoj EM vala

$$\vec{P} = \widetilde{\chi}_e \varepsilon_0 \vec{E}$$

$$\vec{D} = (1 + \widetilde{\chi}_e) \varepsilon_0 \vec{E} = \tilde{\epsilon} \vec{E}$$

$$\tilde{\epsilon} \equiv (1 + \widetilde{\chi}_e) \varepsilon_0 = \tilde{\epsilon}_r \varepsilon_0$$

$$\vec{E}(\vec{r}, t) = \vec{E}_0 \exp\left(\frac{i2\pi\tilde{n}}{\lambda} \vec{q} \cdot \vec{r}\right) \exp(-i\omega t)$$

Koliko je materijal polarizabilan

$$\tilde{n} = n - ik$$

$$\tilde{\epsilon} = \epsilon_1 - i\epsilon_2$$

$$\tilde{\epsilon} = \tilde{n}^2$$

Prijelazi elekrona iz osnovnog u pobuđeno stanje određuju imaginarni dio dielektrične funkcije!

Kramers-Kronig relacija

$$\varepsilon_1(E) - 1 = \frac{2}{\pi} P \int_0^{\infty} \frac{E' \varepsilon_2(E')}{E'^2 - E^2} dE'$$

$$\varepsilon_2(\omega) = \frac{\sigma(\omega)}{\omega}$$

$$\sigma(\omega) = e\mu n$$

$$\varepsilon_2 \propto n$$

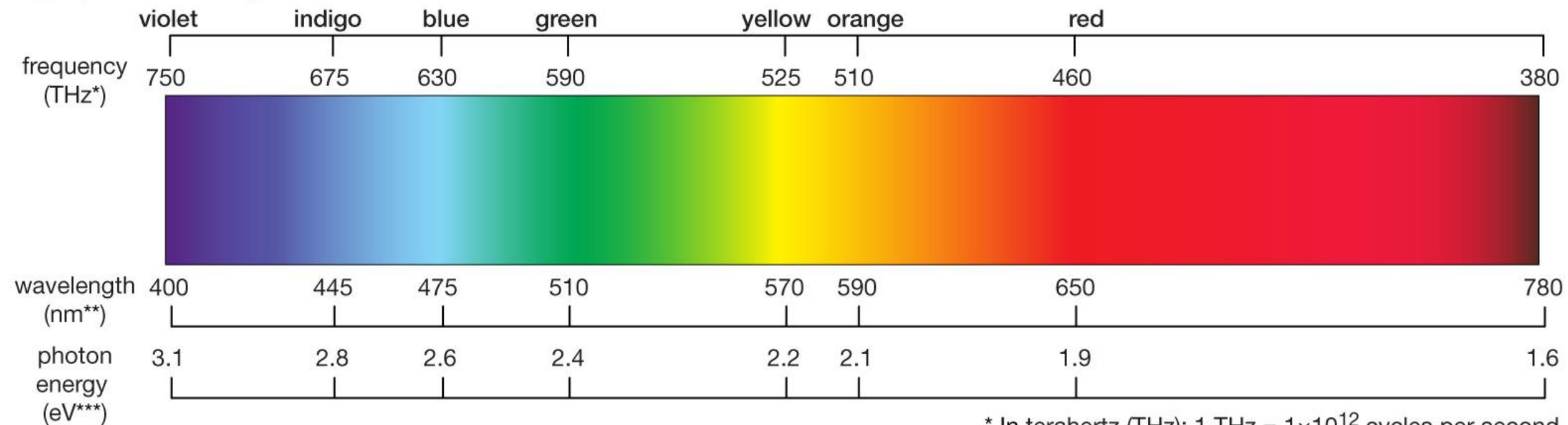
Optička svojstva svih materijala određena su u potpunosti tipom i jakošću optičke apsorpcije koja se dogodi u materijalu

Osnovni mehanizmi kojima se energija svjetlosnog snopa apsorbira u materijalu:

- ◆ Intervrpčana apsorpcija
- ◆ Intravrpčana apsorpcija
- ◆ Apsorpcija slobodnih nosioca naboja

Vidljivi dio spektra

Light, the visible spectrum



* In terahertz (THz); 1 THz = 1×10^{12} cycles per second.

** In nanometres (nm); 1 nm = 1×10^{-9} metre.

*** In electron volts (eV).

H_2Pc – bezmetalni pftalocijanin

- 2 kristalne faze; α i β
- Dvije apsorpcijske vrpce mogu se zapaziti, vrpca blizu **2 eV** (620 nm; Q vrpca) i jedna blizu **3.5 eV** (350 nm; B ili Soret vrpca)
- Obje vrpce pridjeljene su π - π^* pobuđenjima makrocikličkog π sistema sastavljenog od C i N atoma

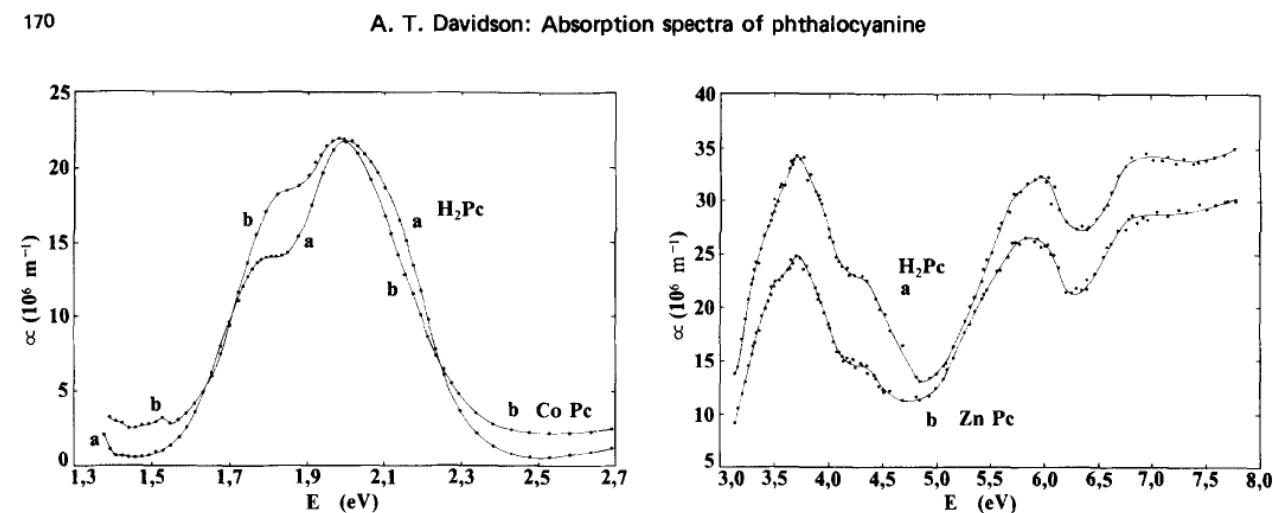
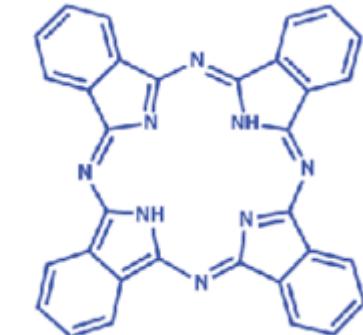


FIG. 3. The visible absorption spectra of (a) H_2Pc ($\lambda = 175 \text{ nm}$) and (b) CoPc ($\lambda = 100 \text{ nm}$) films.

FIG. 5. The absorption spectra between 3.1 and 7.8 eV for (a) H_2Pc ($\lambda = 25 \text{ nm}$) and (b) ZnPc ($\lambda = 40 \text{ nm}$) films.

J. Chem. Phys. 77, 168 (1982); doi: 10.1063/1.443636

TABLE I. Maxima (in eV) seen in the absorption spectra of phthalocyanine films. The main peak in each band is underlined. nr means not resolved.

Compound	Visible (Q)	Soret (B)	Variable (N)	(C)	Far UV hand
H_2Pc	1.79 <u>2.00</u>	3.33 3.53 <u>3.74</u>	4.29	5.66	<u>5.93</u> 6.94 nr

PTCDI – N,N'-dimetilperilen-3,4:9,10-tetrakarboksilni diimid

- PTCDI ima područje apsorpcije centrirano pri 494 nm (**2.5 eV**) i pri 580 nm (**2.14 eV**).
 - Q vrpca: jedno rame pri 2.5 eV (π - π^* pobuđenje), jedan maksimum pri 2.14 eV (vrh eksitonika)
 - B vrpca : pri **3.35 eV** ; π - π^* pobuđenje
 - N vrpca: Slaba apsorpcija pri **4~4.75 eV** (izmjena naboja (CT) iz sp_z mješane orbitale u elektronski sistem makroskopskog prstena PTCDI-a)
 - C vrpca: pri **5.6 eV** ; π - π^* pobuđenje

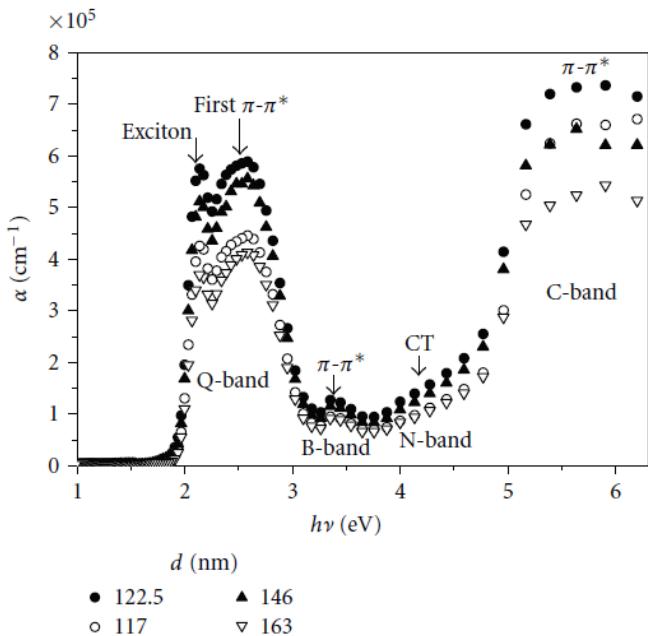


FIGURE 8: Optical absorption spectra of PTCDI thin films.

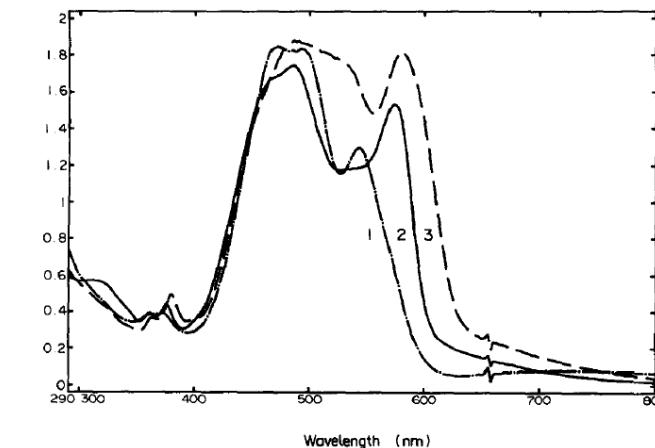
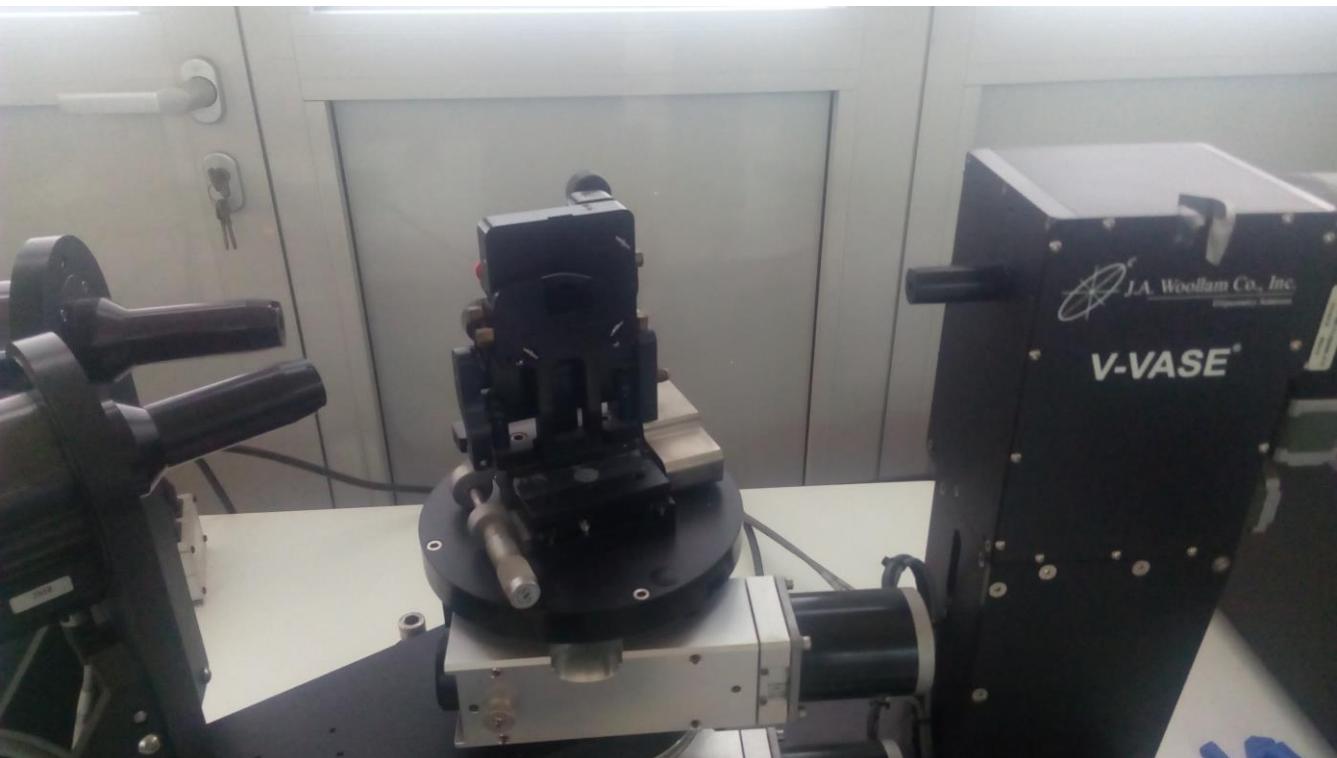
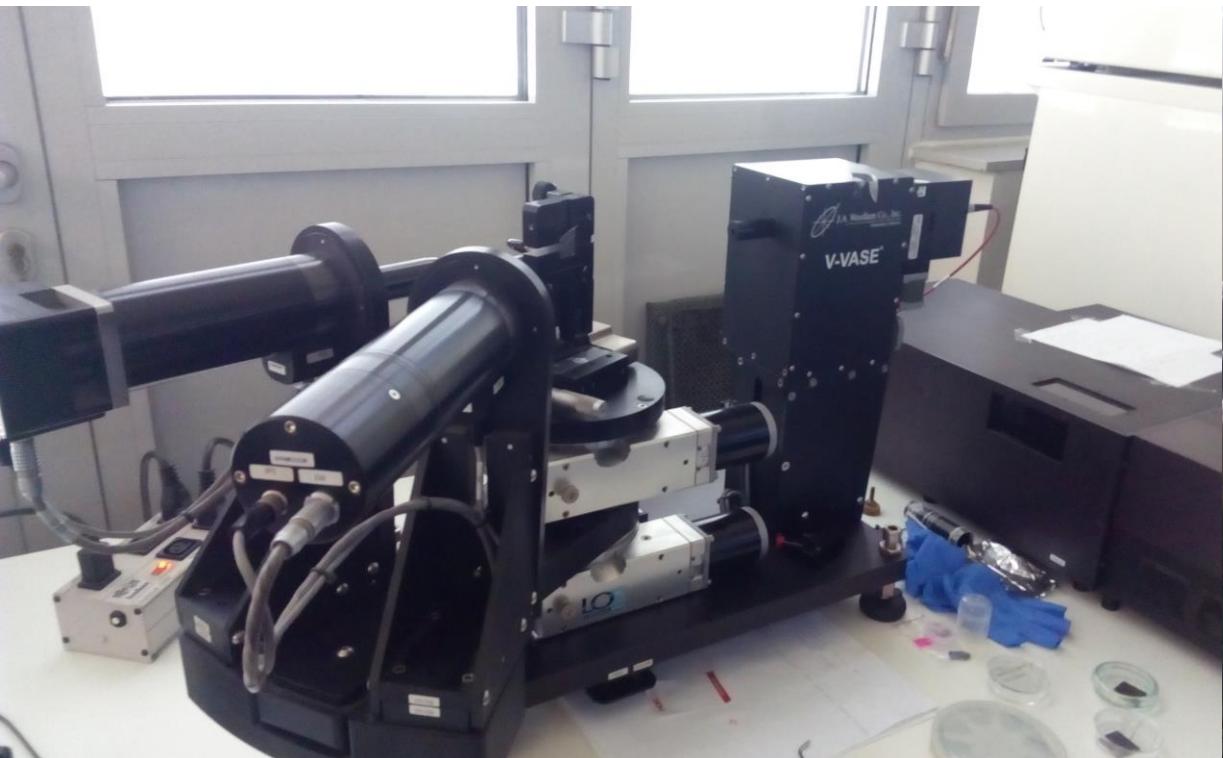


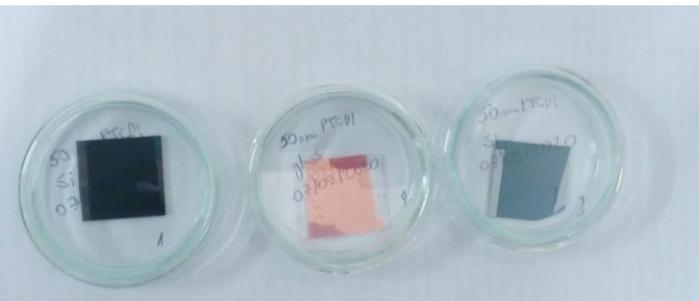
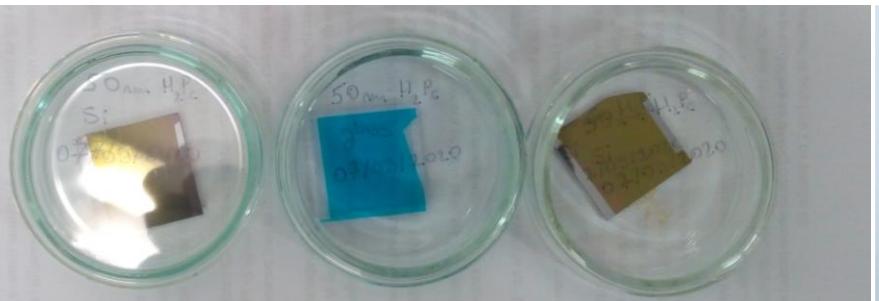
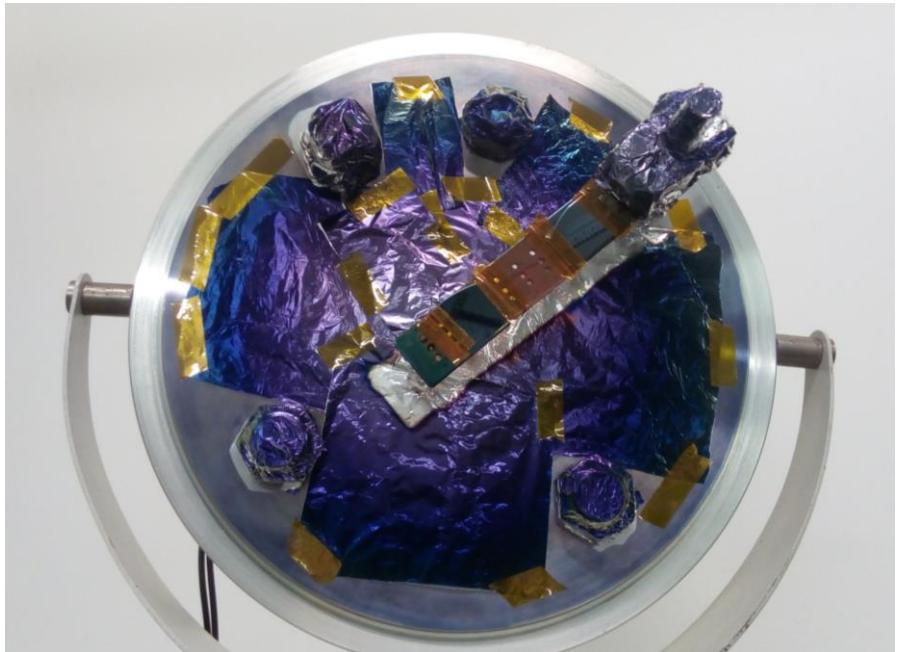
Fig. 1. Absorption spectra of PTCDPh (1), PTCDMe (2) and PTCDI (3).

M. M. El-Nahhas, H. Abdel-Khalek,
E. Salem, "Structural and Optical
Properties of Nanocrystalline
3,4,9,10-Perylene-Tetracarboxylic-
Diimide Thin Film,,
<https://doi.org/10.1155/2012/698934>

W-VASE elipsometar

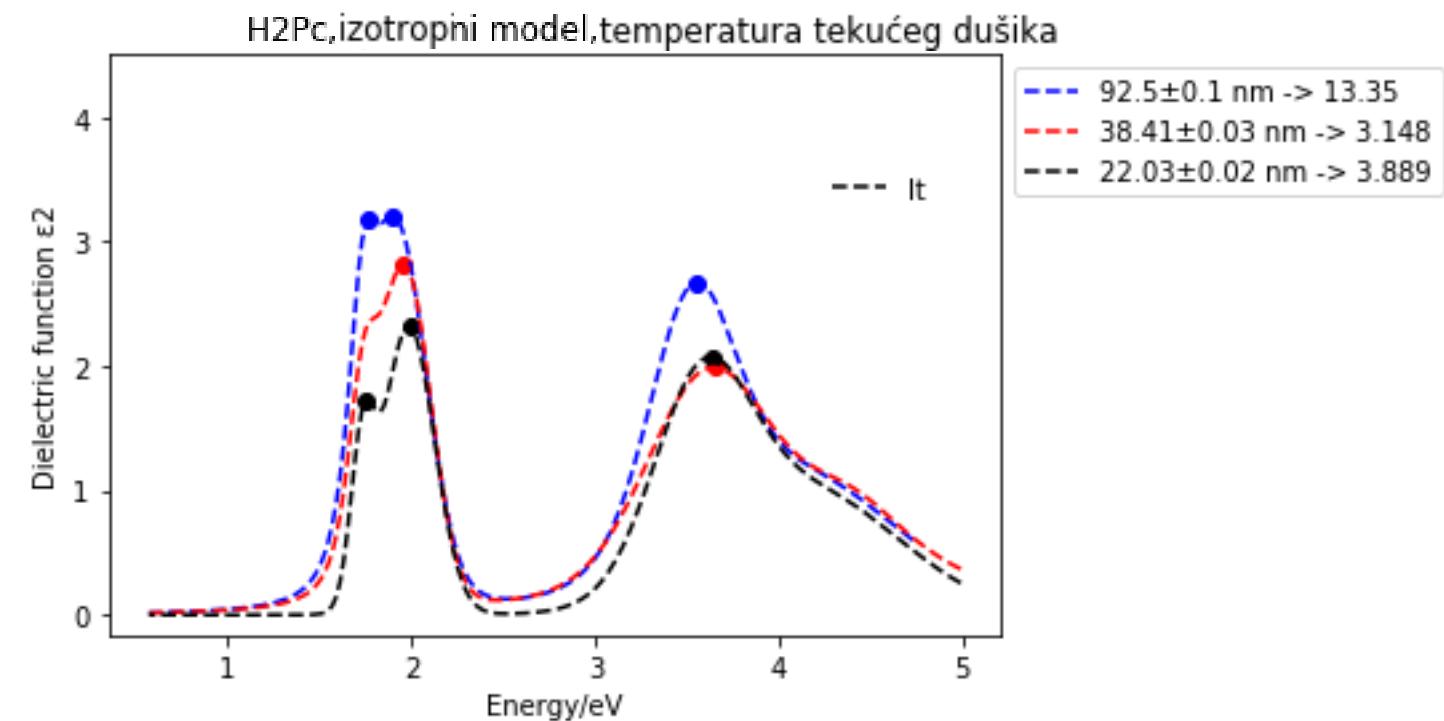
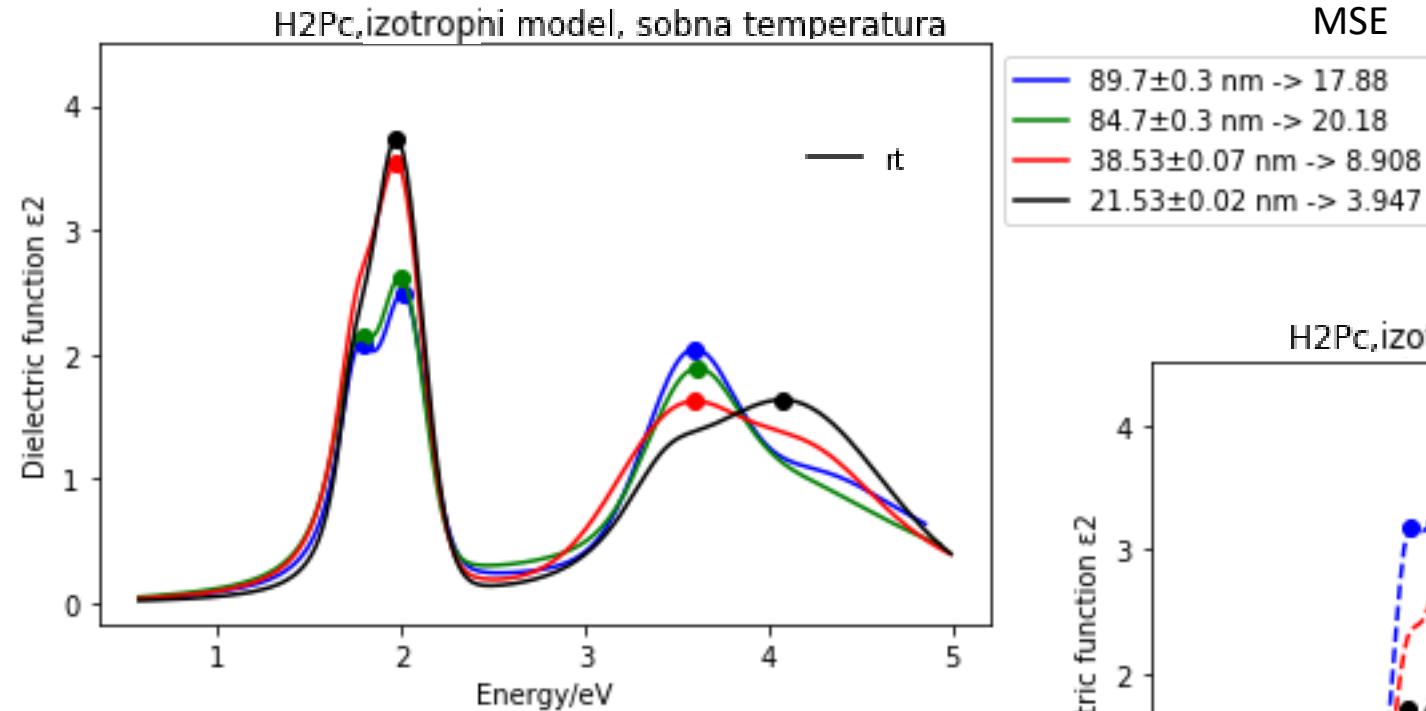


Termalna evaporacija

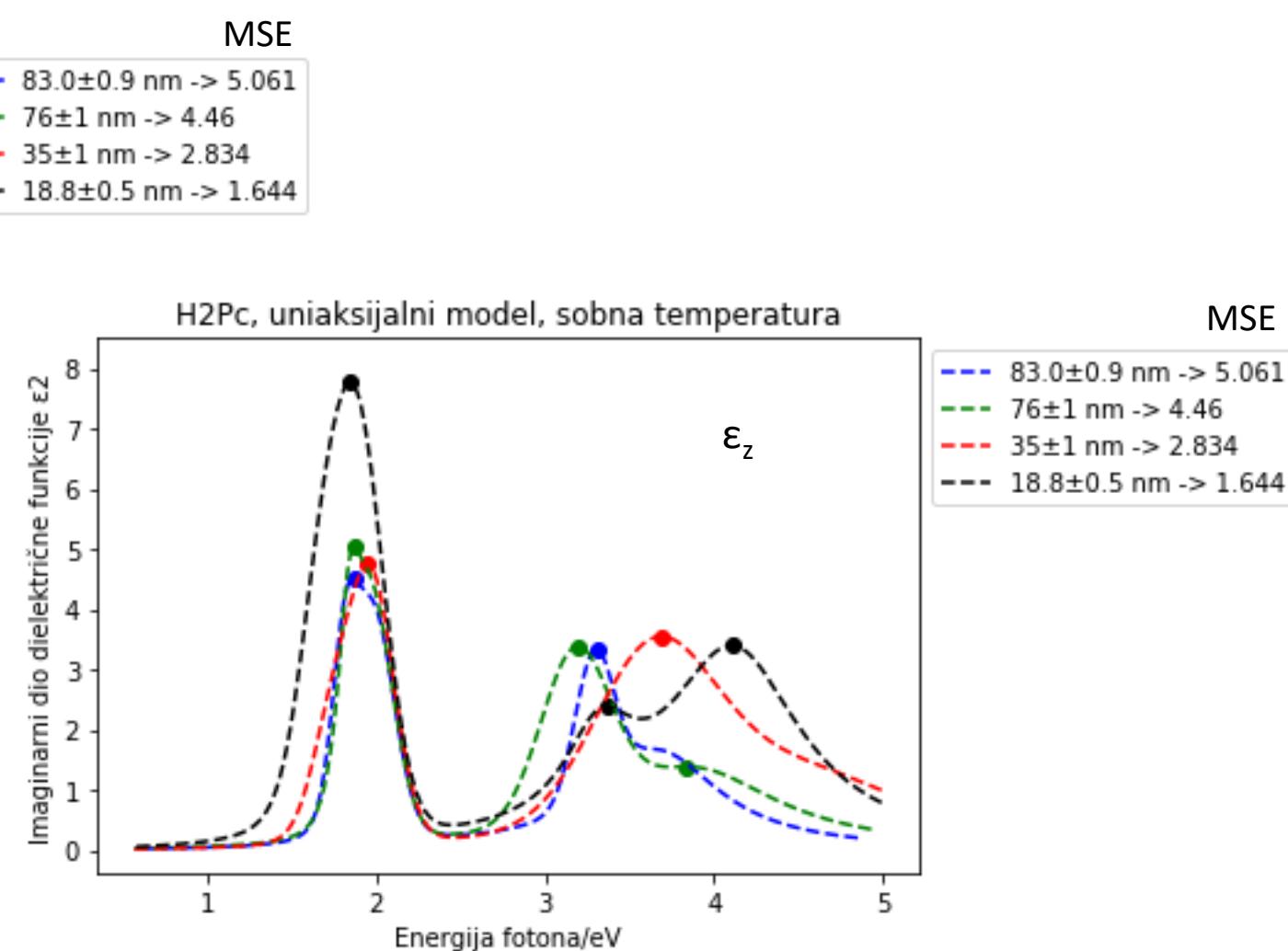
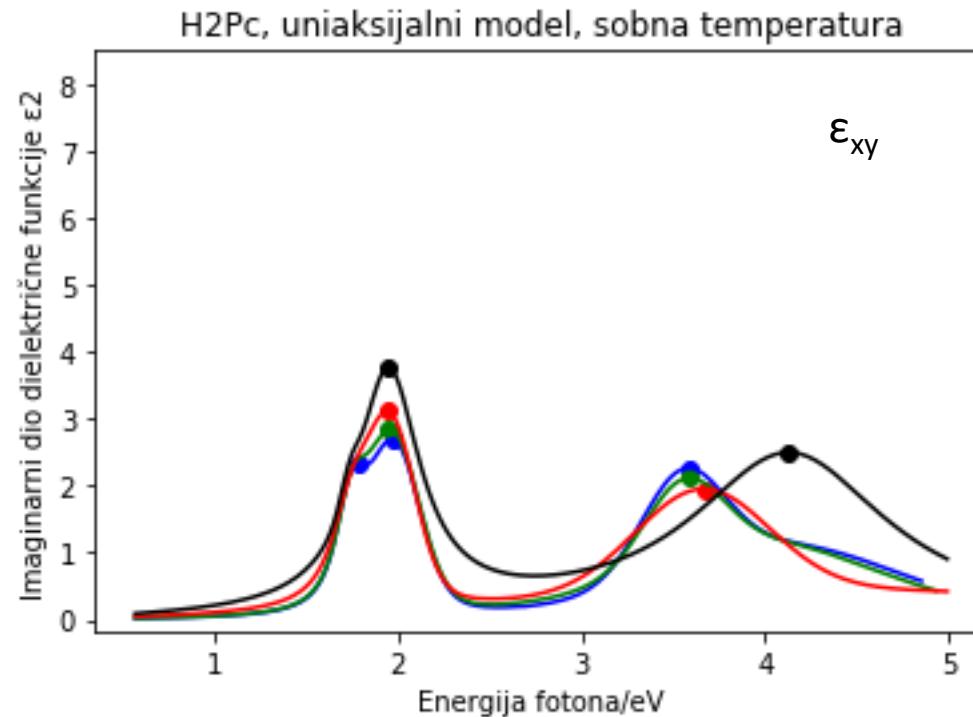


Rezultati mjerenja
(modeliranja)

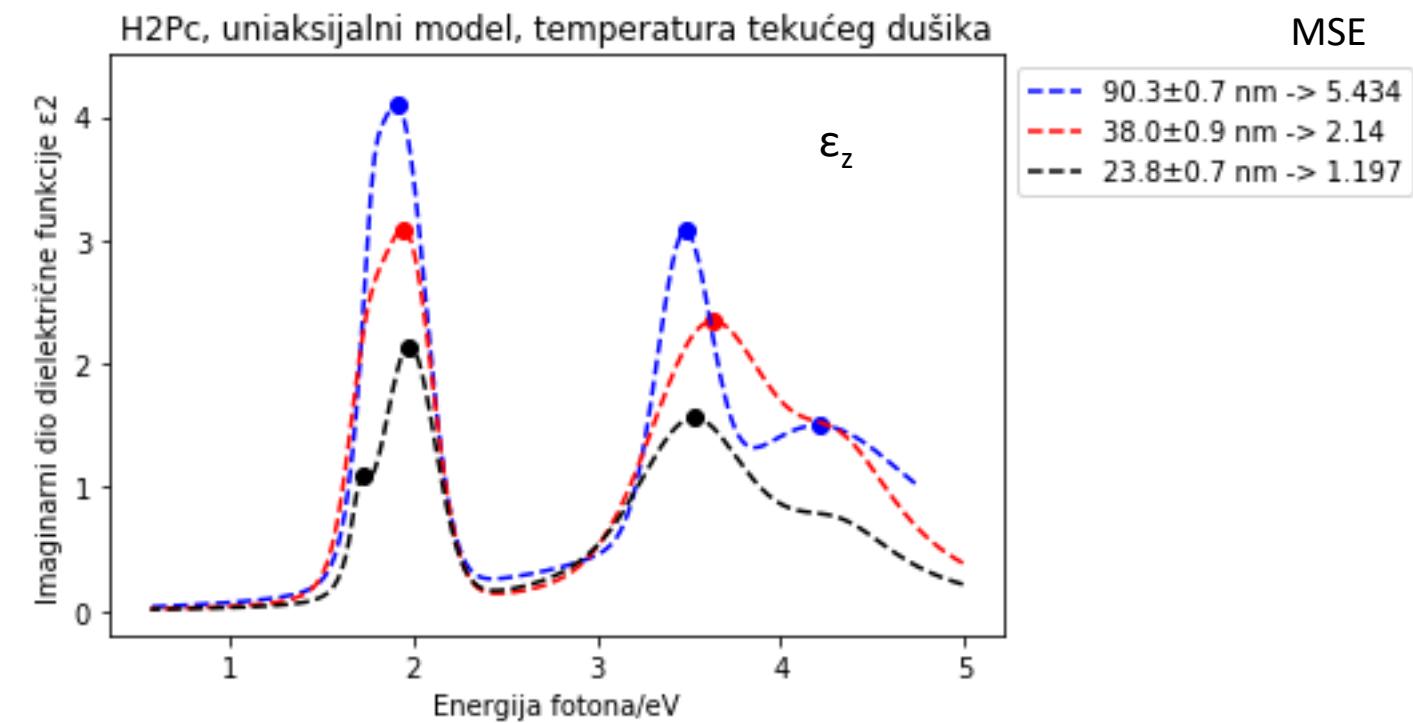
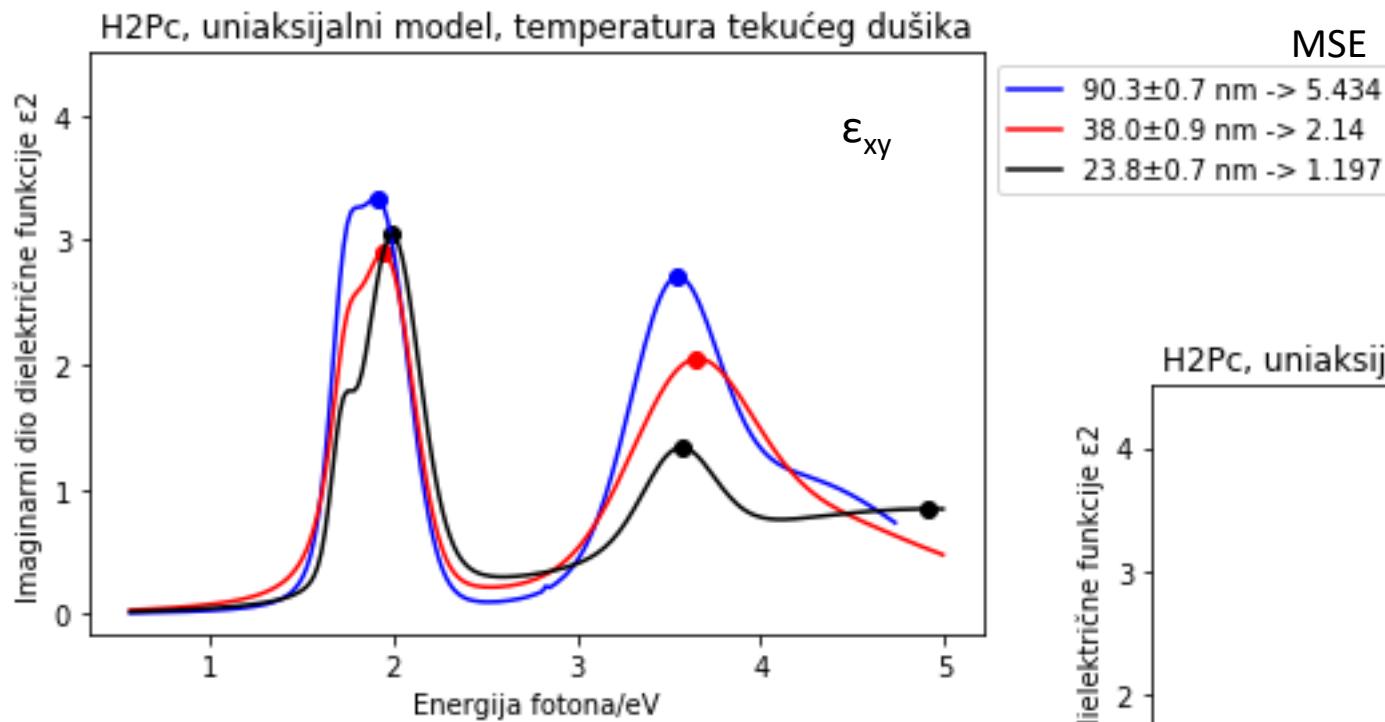
H_2Pc , izotropni model



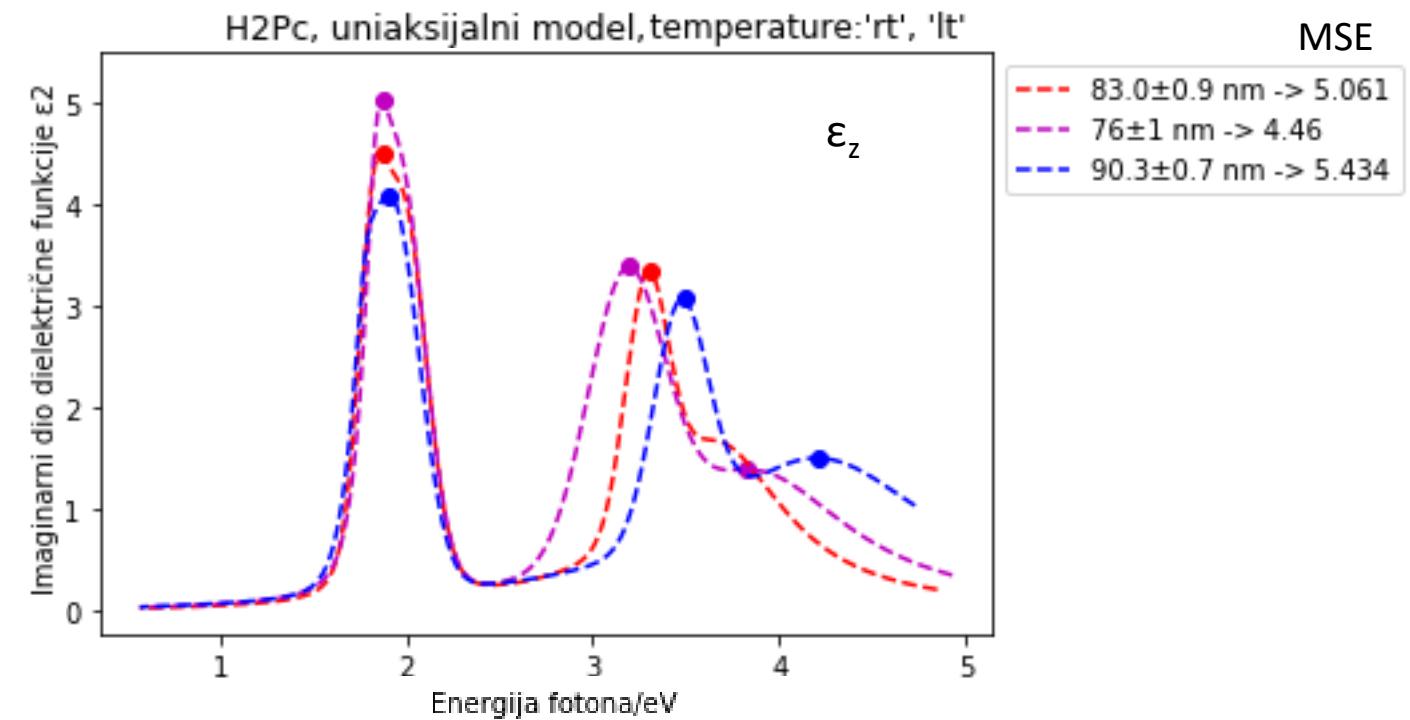
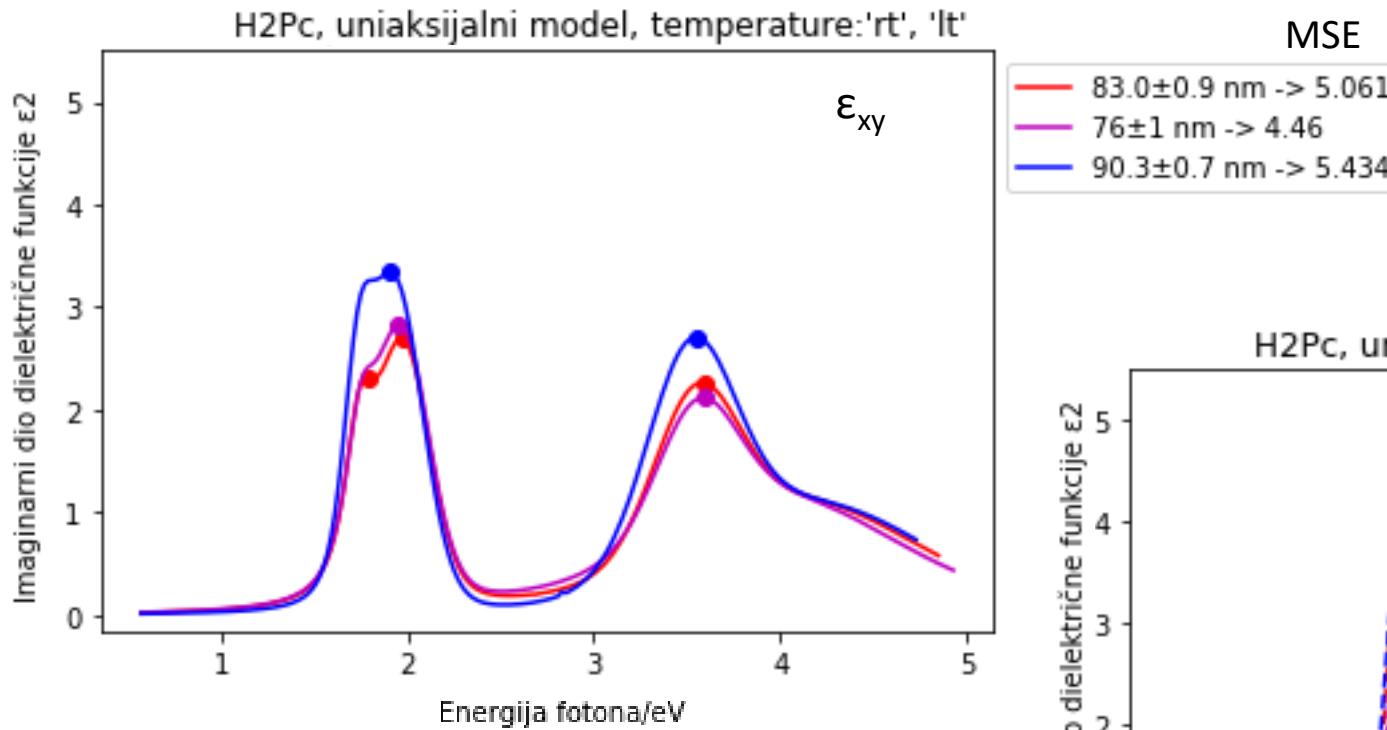
H_2Pc , uniaksijani model: 20°C



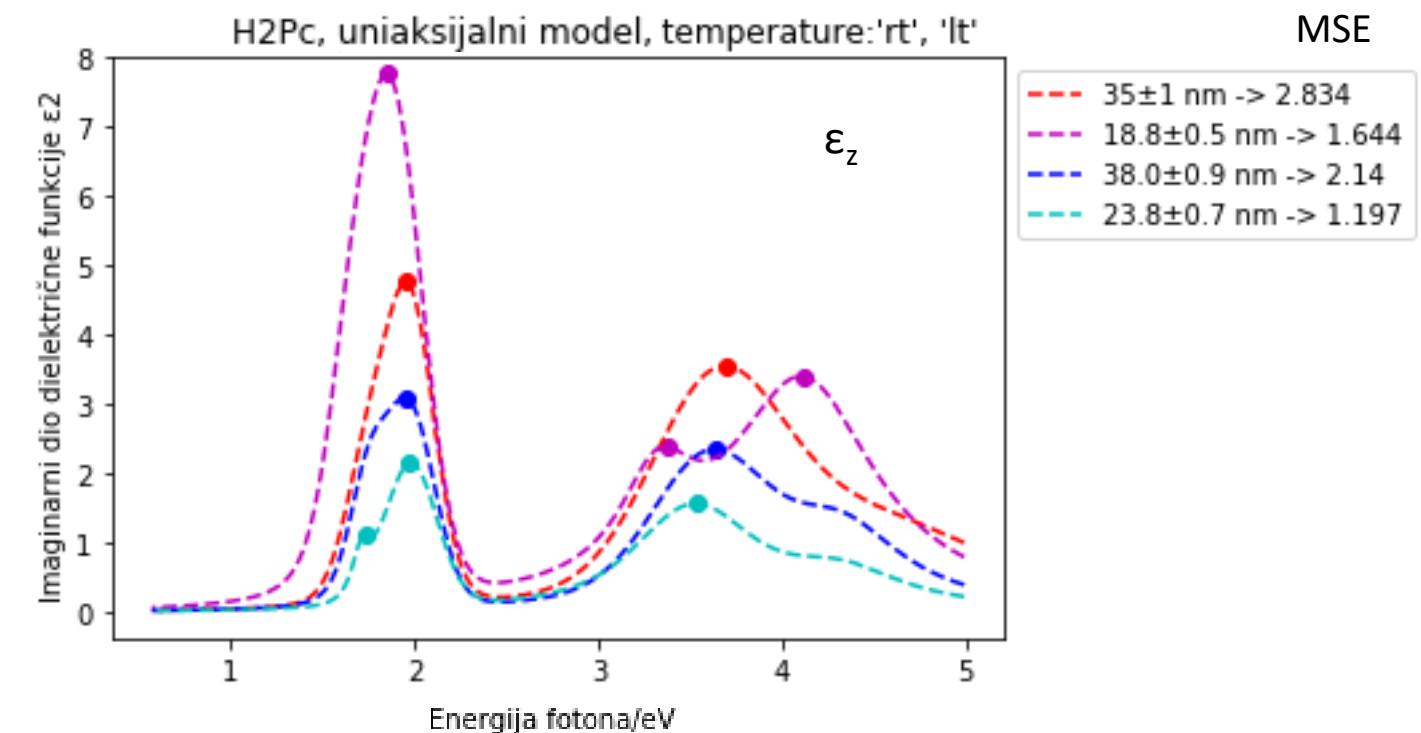
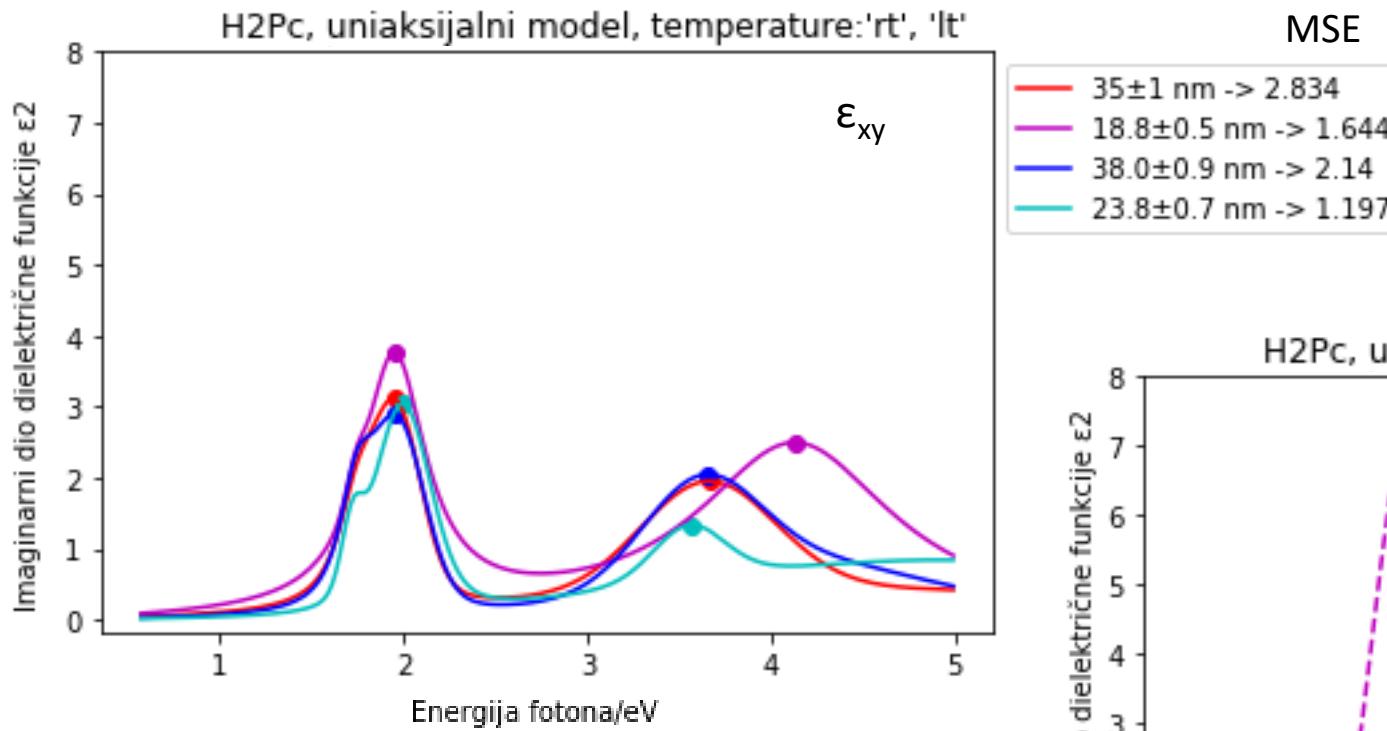
H_2Pc , uniaksijani model: -160°C



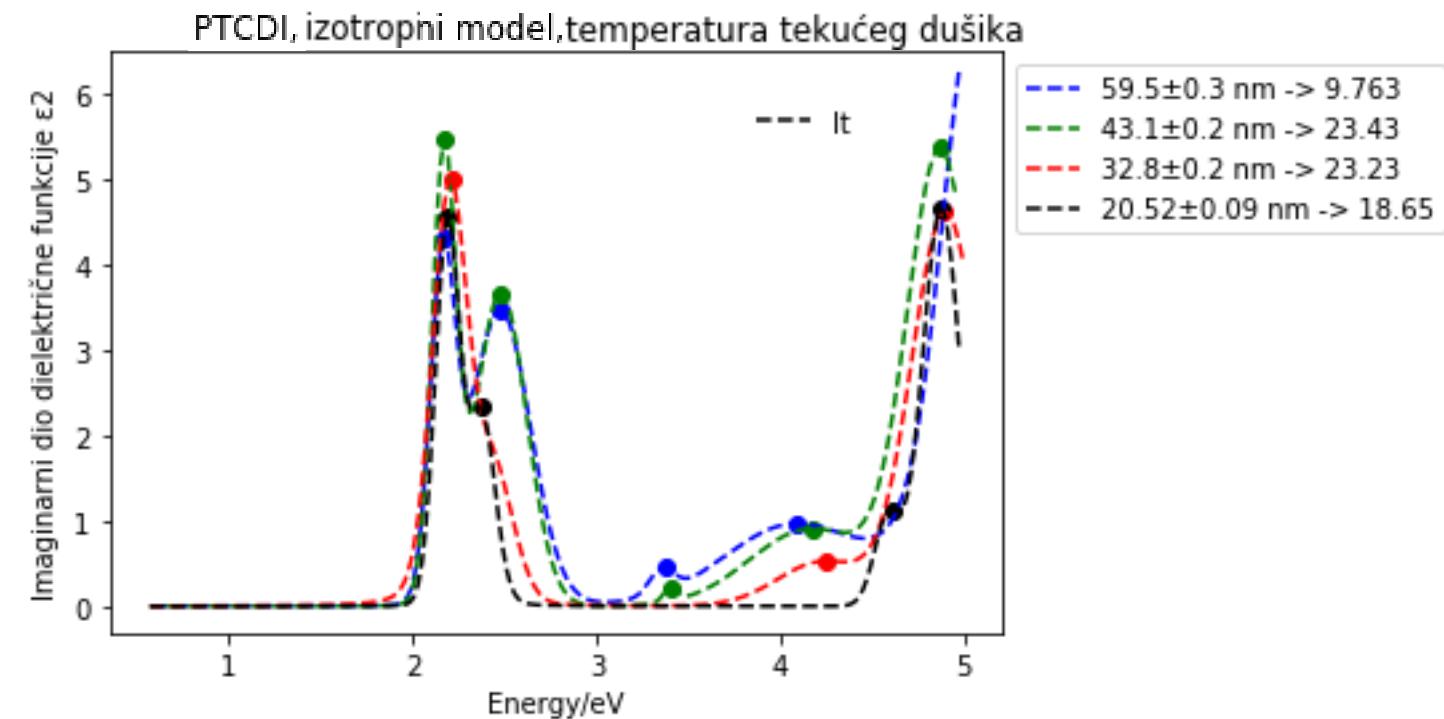
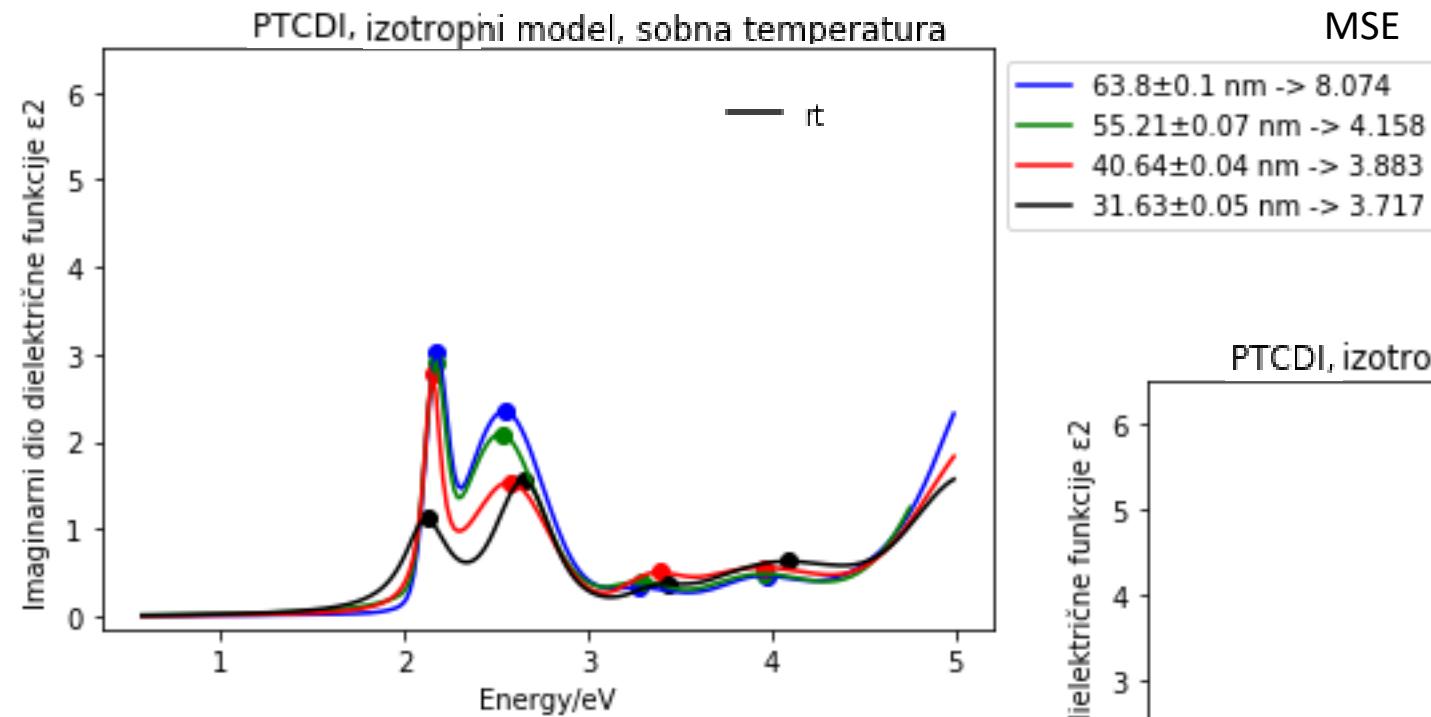
H_2Pc , uniaksijani model: Deblji slojevi



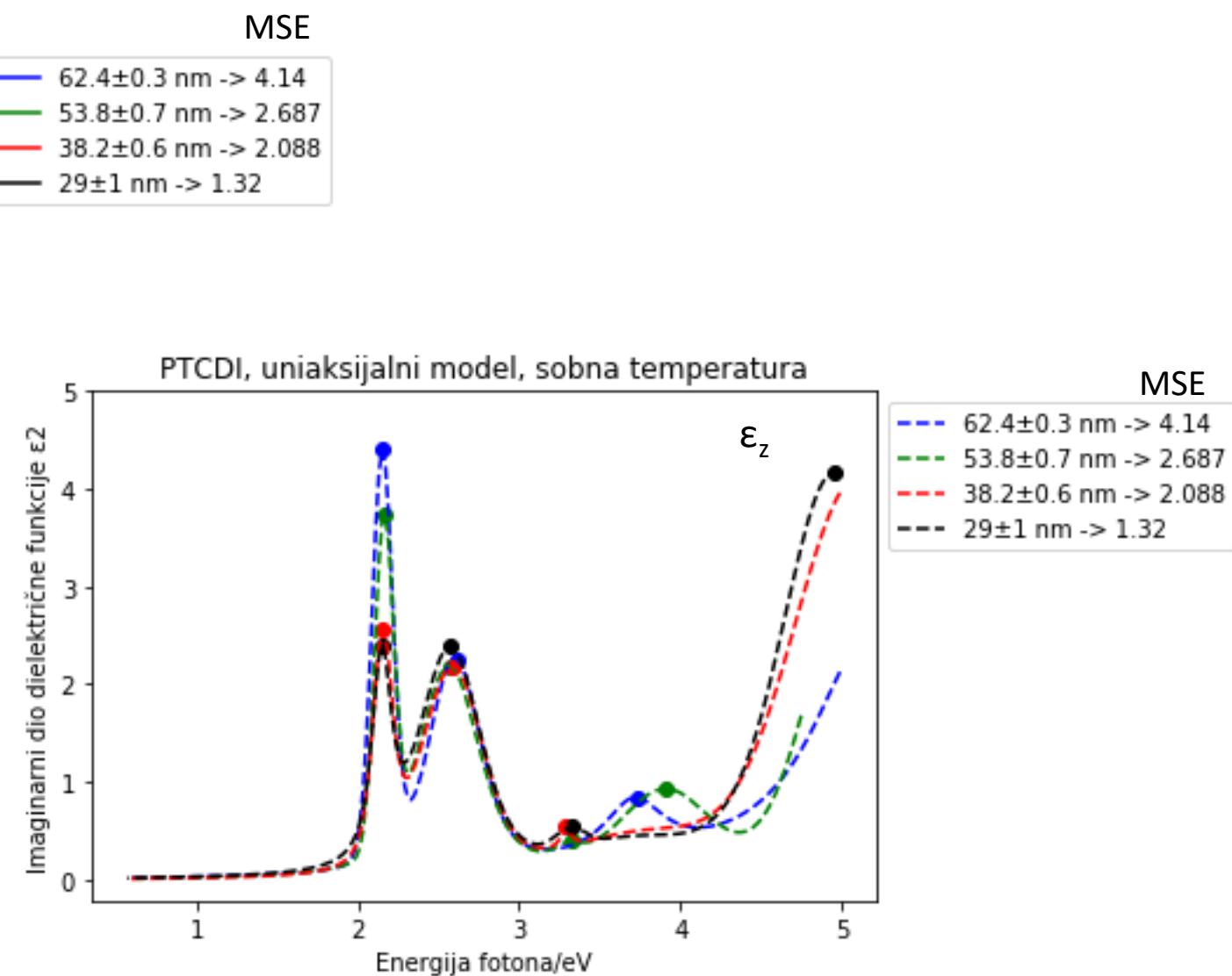
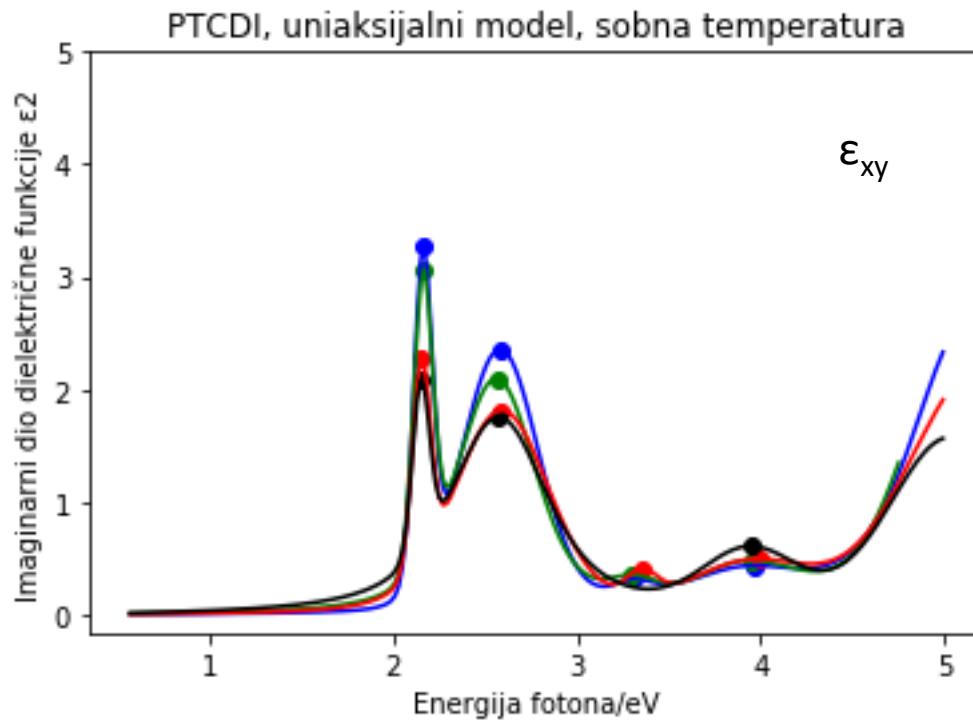
H_2Pc , uniaksijalni model: Deblji slojevi



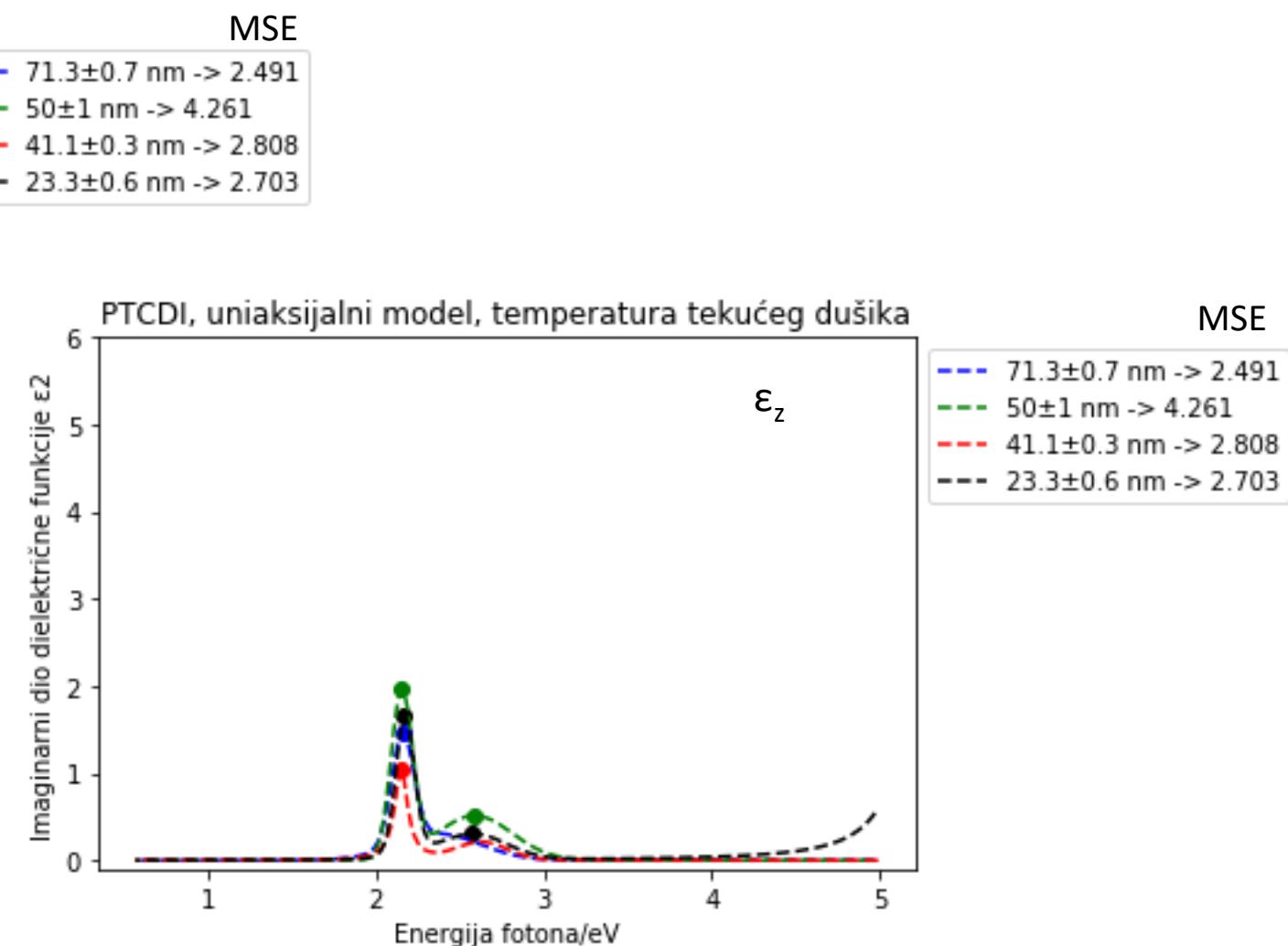
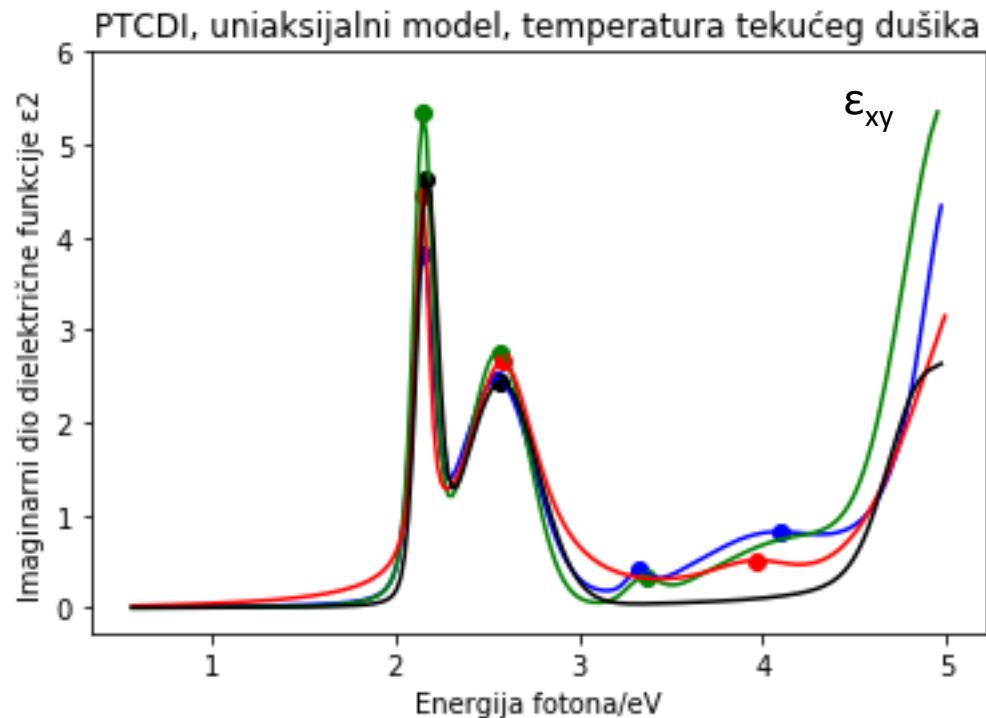
PTCDI, izotropni model



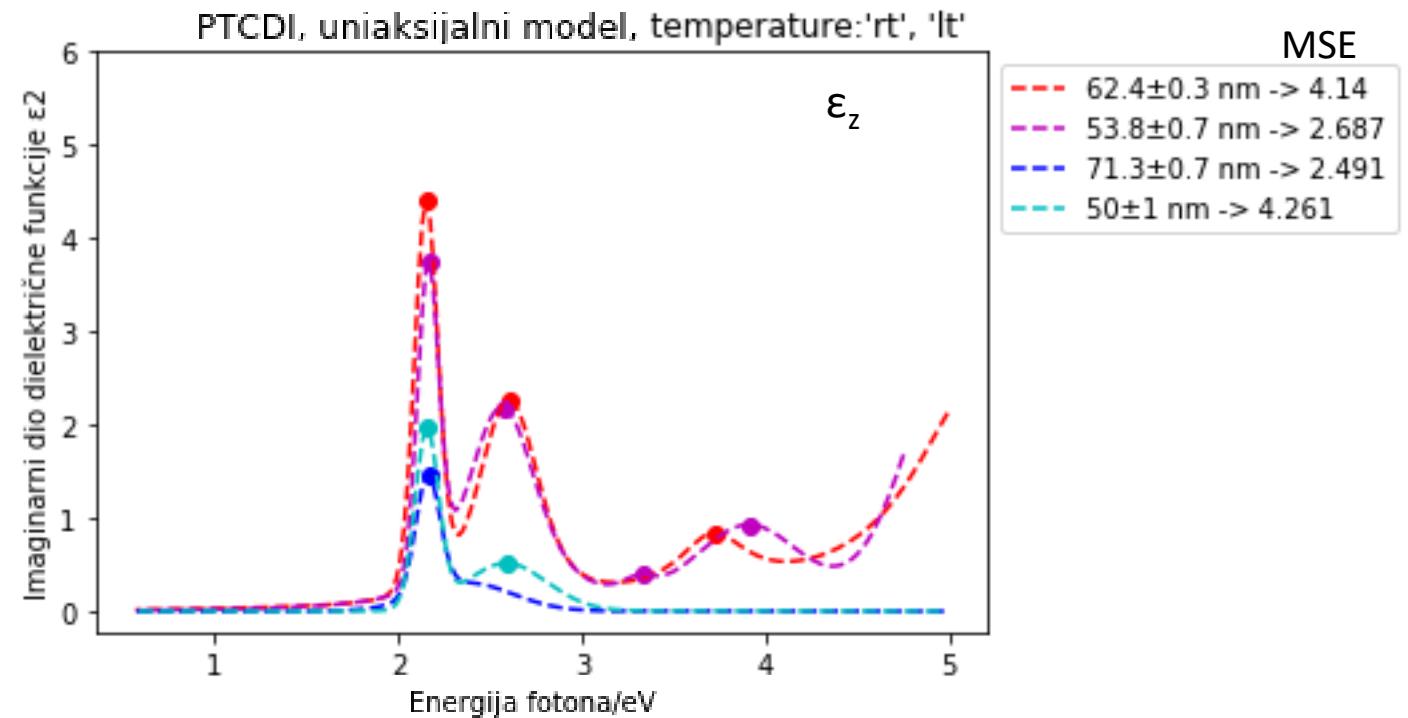
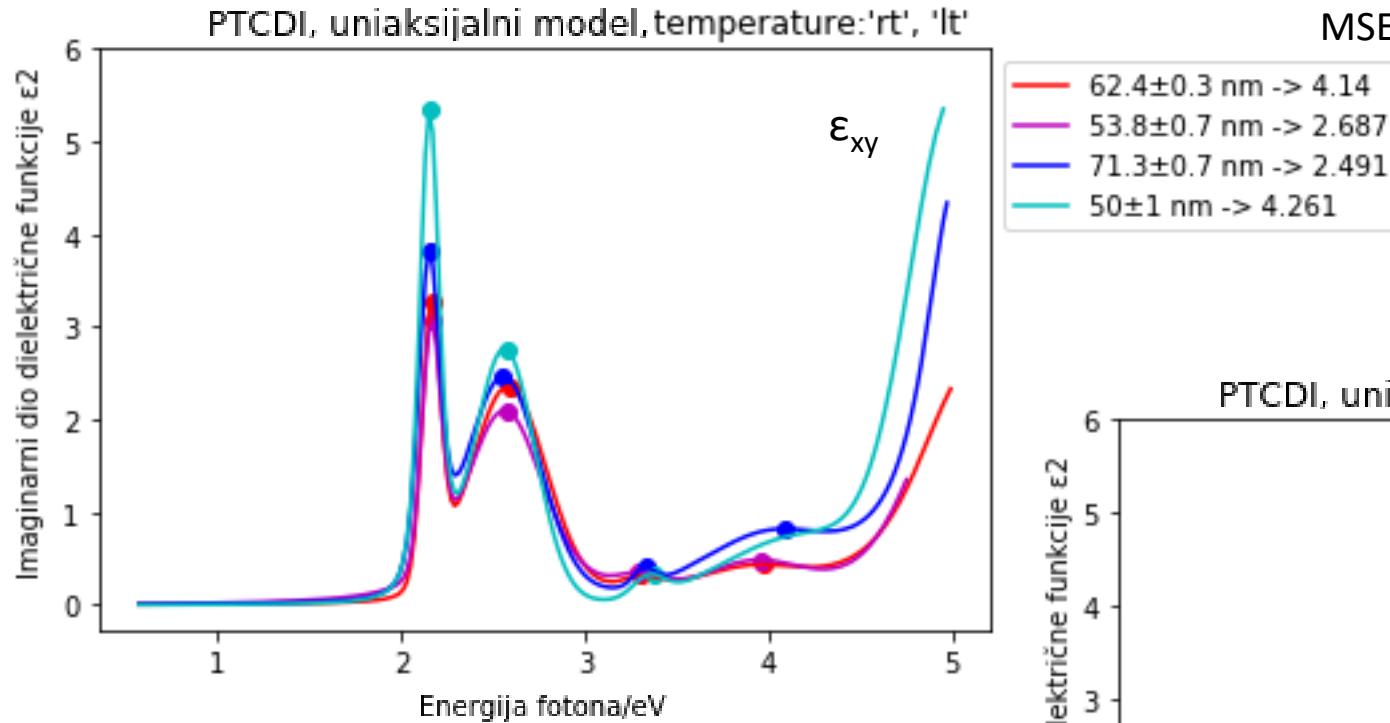
PTCDI, uniaksijalni model: 20°C



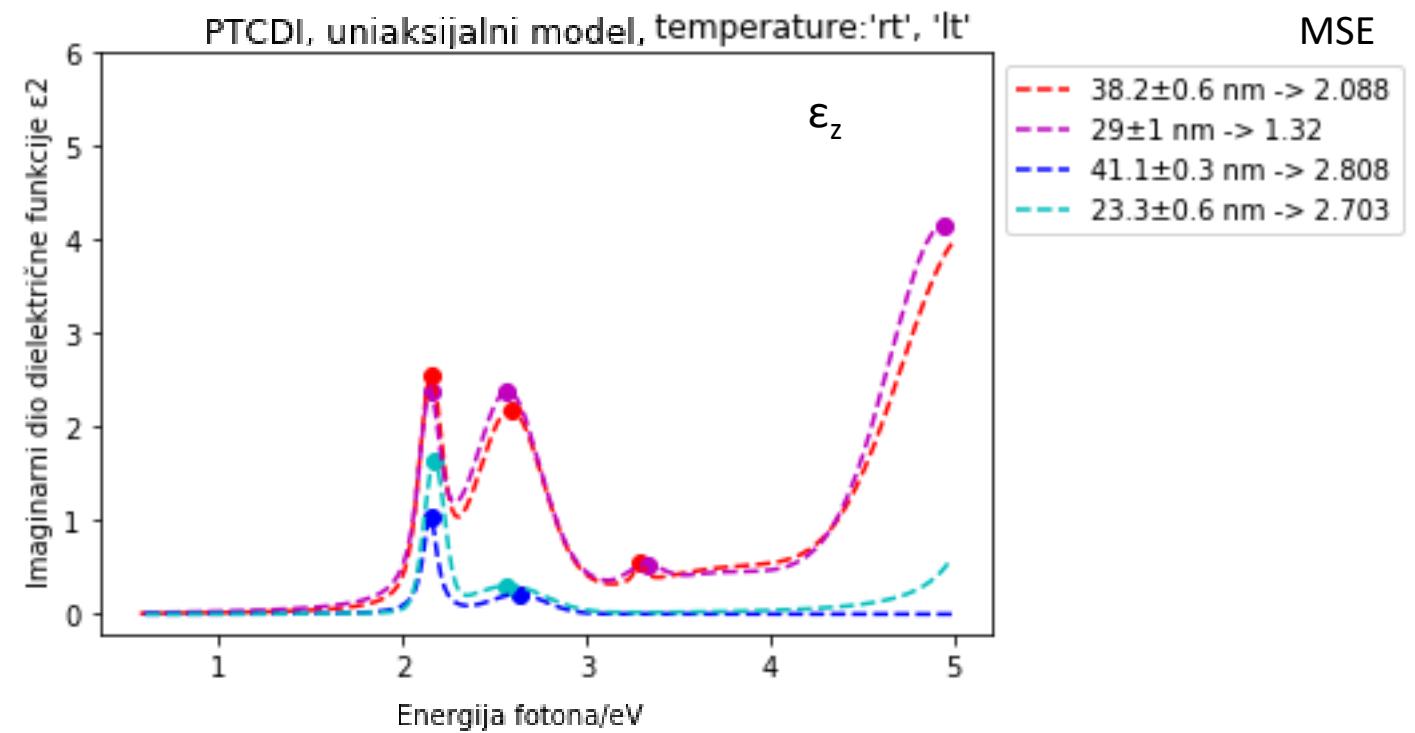
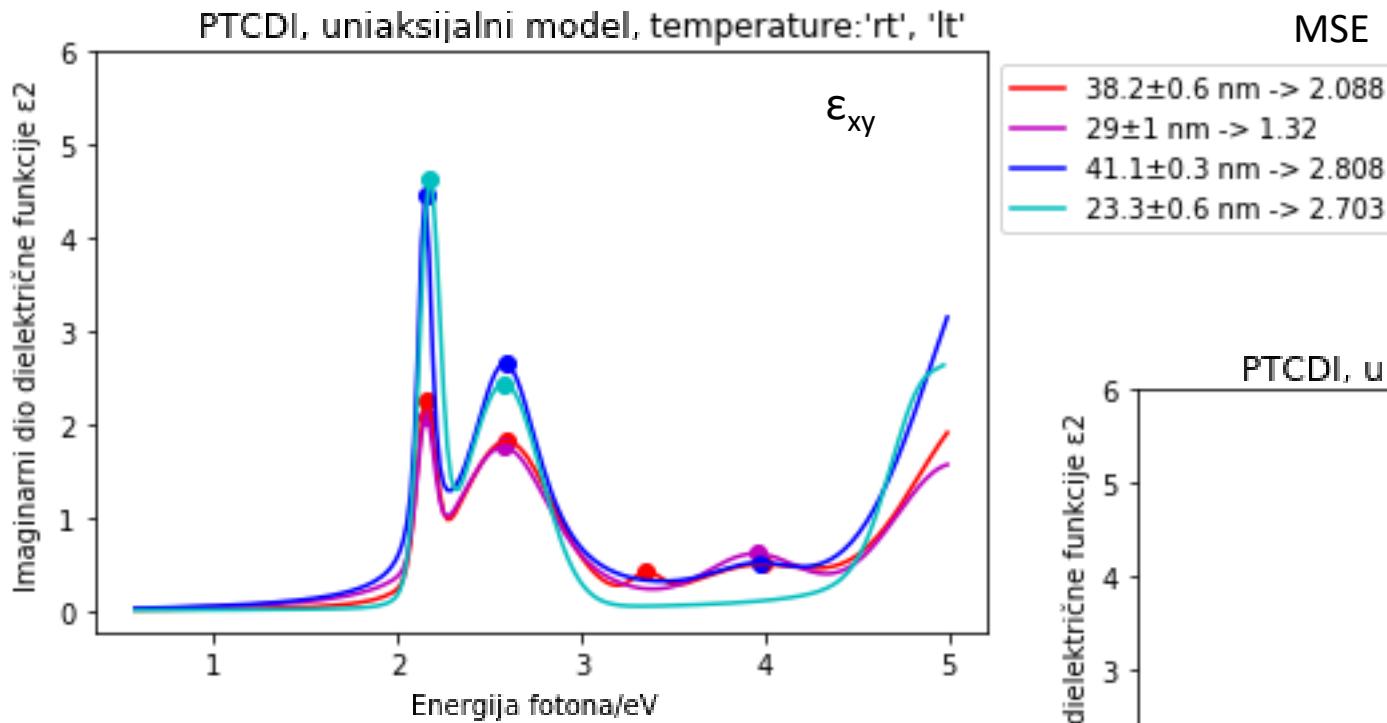
PTCDI, uniaksijani model: -160°C



PTCDI, uniaksijani model: Deblji slojevi



PTCDI, uniaksijani model: Tanji slojevi



Zaključak

	H ₂ Pc				PTCDI			
	Debljina ↑				Debljina ↑			
	ε_{xy}		ε_z		ε_{xy}		ε_z	
	E	Amp	E	Amp	E	Amp	E	Amp
RT	* B vrpca; ↓	↓	B vrpca; ↓	* ↓	.	↑	.	↑
LT	.	↑	.	↑	.	↑	.	↑

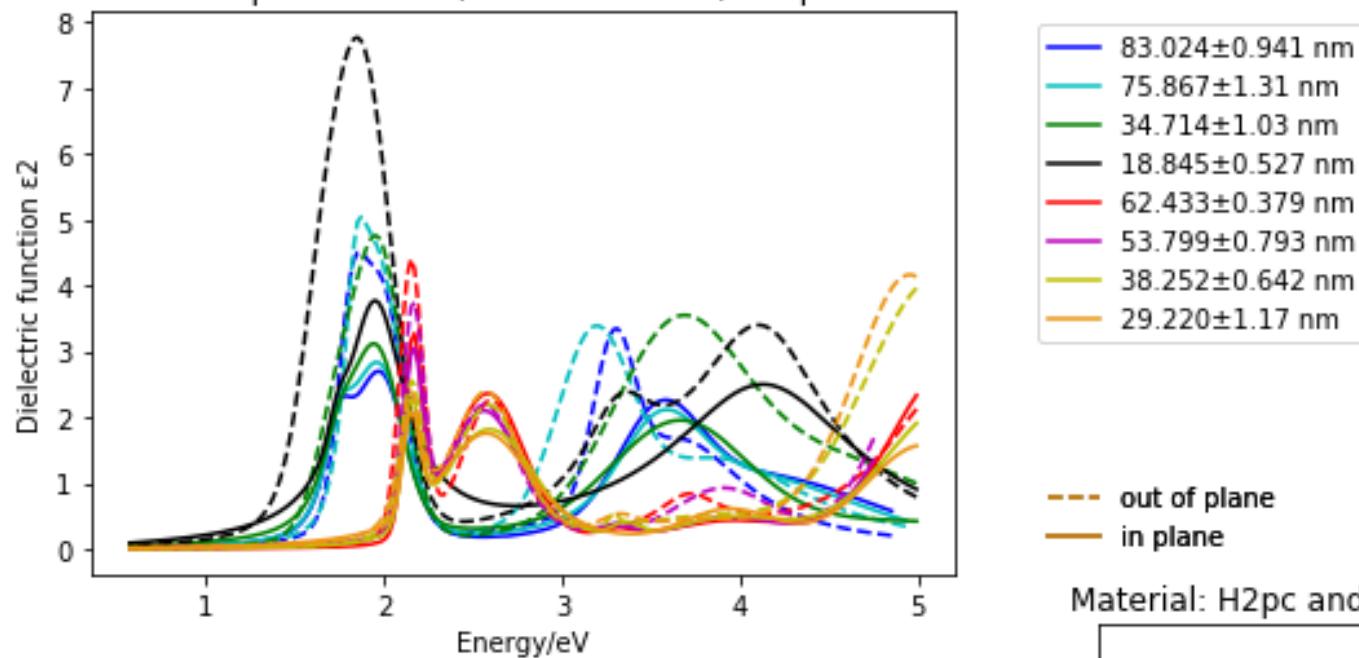
	H ₂ Pc				PTCDI				H ₂ Pc				PTCDI				
	ε_{xy}		ε_z		ε_{xy}		ε_z		RT		LT		RT		LT		
	E	Amp	E	Amp	E	Amp	E	Amp	E	Amp	E	Amp	E	Amp	E	Amp	
Temp ↑	N	↓	N	↑	.	↓	C vrpc a!	↑	→L	.	↑	.	N	.	↑	C vrpc a ?	↓

Zaključak

- Elipsometrija = moćna metoda za optičku karakterizaciju materijala
- Izotropni model nedovoljan za modeliranje H₂Pc i PTCDI tankih slojeva
- Nužno koristiti anikasijani model
- Zamijećena ovisnost ϵ_{xy} i ϵ_z o debljini i temperaturi za oba materijala
- Veliki utjecaj temperature depozicije na komponentu ϵ_z uzorka PTCDI-a
- Hrapavost u modelu?
- Potvrda modela?

Hvala na pažnji!

Material: H2pc and PTCDI, model: uniaxial, temperature:'rt'



Material: H2pc and PTCDI, model: uniaxial, temperature:'lt'

